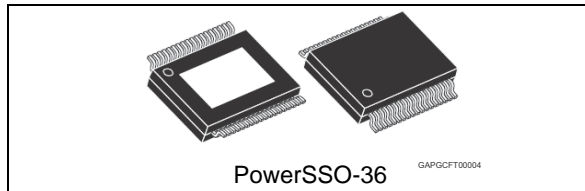


## Double channel high-side driver with MultiSense analog feedback for automotive applications

Datasheet - preliminary data



- Configurable latch-off on overtemperature or power limitation with dedicated fault reset pin
- Loss of ground and loss of  $V_{CC}$
- Reverse battery through self turn-on
- Electrostatic discharge protection

### Features

Max transient supply voltage	$V_{CC}$	41 V
Operating voltage range	$V_{CC}$	4 to 28 V
Typ. on-state resistance (per Ch)	$R_{ON}$	12 m $\Omega$
Current limitation (typ)	$I_{LIMH}$	75 A
Standby current (max)	$I_{STBY}$	0.5 $\mu$ A

- General
  - Double channel smart high side driver with MultiSense analog feedback
  - Very low standby current
  - Compatible with 3 V and 5 V CMOS outputs
- MultiSense diagnostic functions
  - Multiplexed analog feedback of: load current with high precision proportional current mirror,  $V_{CC}$  supply voltage and  $T_{CHIP}$  device temperature
  - Overload and short to ground (power limitation) indication
  - Thermal shutdown indication
  - Off-state open-load detection
  - Output short to  $V_{CC}$  detection
  - Sense enable/ disable
- Protections
  - Undervoltage shutdown
  - Overvoltage clamp
  - Load current limitation
  - Self limiting of fast thermal transients

### Applications

- All types of Automotive resistive, inductive and capacitive loads
- Specially intended for Automotive Turn Indicators (up to 3 x P27W or SAE1156 and 2 x R5W paralleled or Automotive Headlamps)

### Description

The VND7012AY-E is a double channel high-side driver manufactured using ST proprietary VIpower<sup>®</sup> M0-7 technology and housed in PowerSSO-36 package. The device is designed to drive 12 V automotive grounded loads through a 3 V and 5 V CMOS-compatible interface, providing protection and diagnostics.

The device integrates advanced protective functions such as load current limitation, overload active management by power limitation and overtemperature shutdown with configurable latch-off.

A  $\overline{\text{FaultRST}}$  pin unlatches the output in case of fault or disables the latch-off functionality.

A dedicated multifunction multiplexed analog output pin delivers sophisticated diagnostic functions including high precision proportional load current sense, supply voltage feedback and chip temperature sense, in addition to the detection of overload and short circuit to ground, short to  $V_{CC}$  and off-state open-load.

A sense enable pin allows off-state diagnosis to be disabled during the module low-power mode as well as external sense resistor sharing among similar devices.

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# 1 Block diagram and pin description

Figure 1. Block diagram

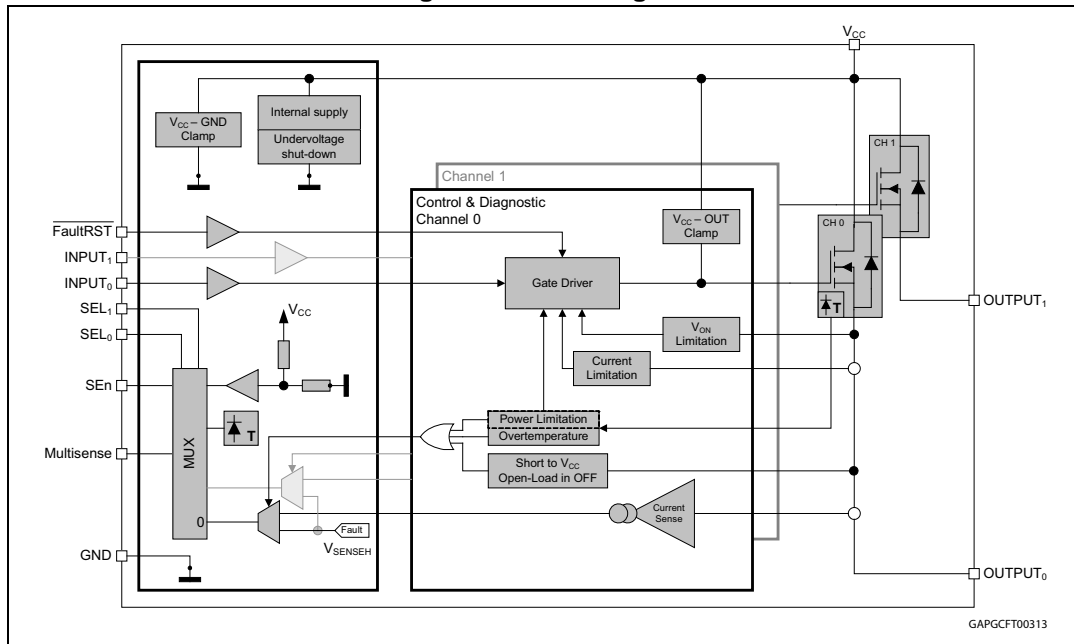


Table 1. Pin functions

Name	Function
V <sub>CC</sub>	Battery connection.
OUTPUT <sub>0,1</sub>	Power output.
GND	Ground connection.
INPUT <sub>0,1</sub>	Voltage controlled input pin with hysteresis, compatible with 3V and 5V CMOS outputs. They control output switch state.
MultiSense	Multiplexed analog sense output pin; delivers a current proportional to the selected diagnostic: load current, supply voltage or chip temperature.
SEn	Active high compatible with 3V and 5V CMOS outputs; it enables the MultiSense diagnostic pin.
SEL <sub>0,1</sub>	Active high compatible with 3V and 5V CMOS outputs; they address the MultiSense multiplexer.
$\overline{\text{FaultRST}}$	Active low compatible with 3V and 5V CMOS outputs; unlatches the output in case of fault; if kept low, sets the outputs in auto-restart mode.

Figure 2. Configuration diagram (top view)

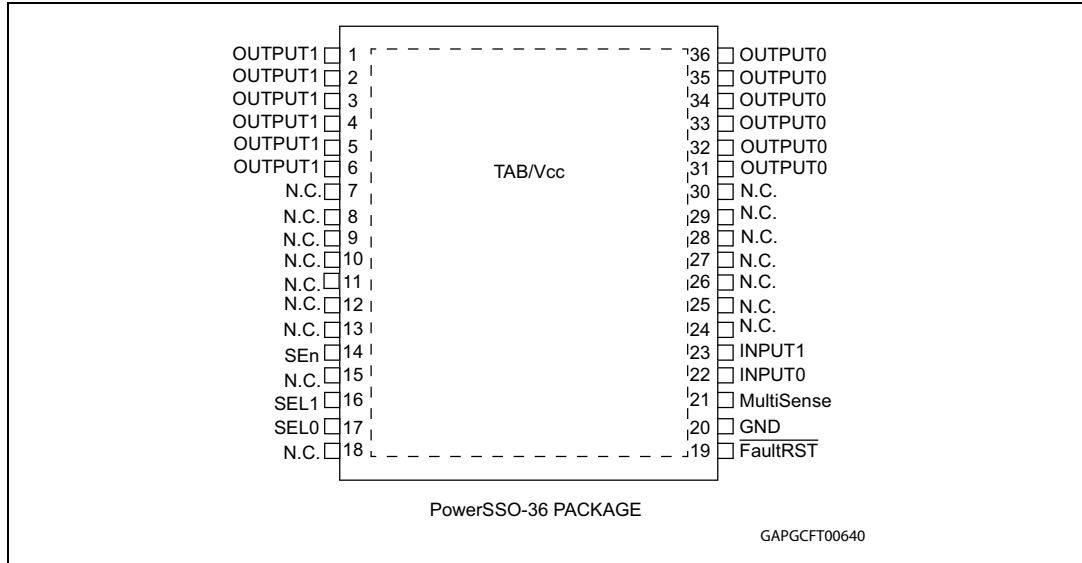


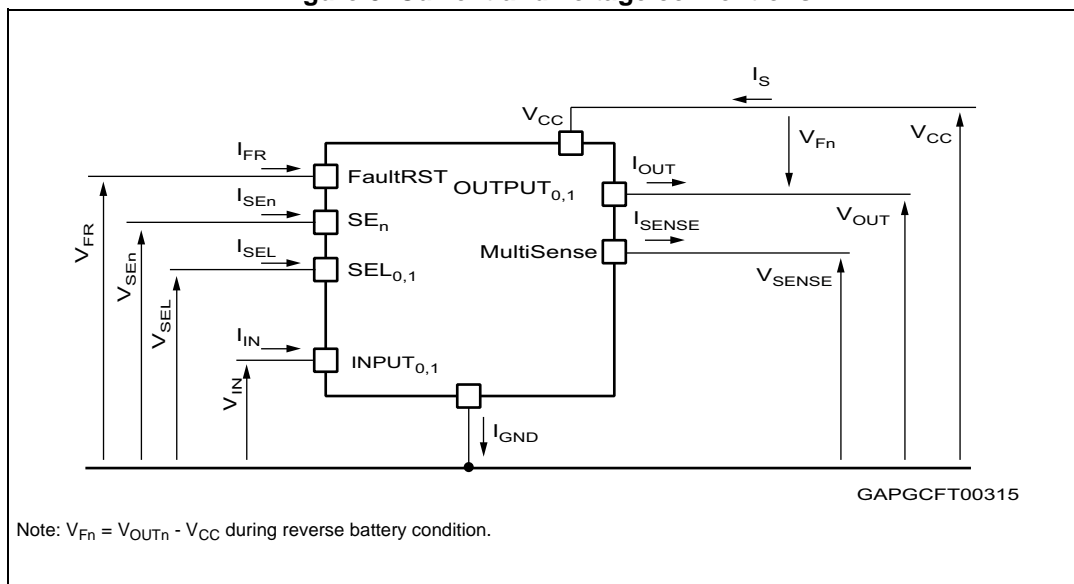
Table 2. Suggested connections for unused and not connected pins

Connection/pin	MultiSense	N.C.	Output	Input	SEn, SELx, FaultRST
Floating	Not allowed	X <sup>(1)</sup>	X	X	X
To ground	Through 1 kΩ resistor	X	Not allowed	Through 15 kΩ resistor	Through 15 kΩ resistor

1. X: do not care.

## 2 Electrical specification

Figure 3. Current and voltage conventions



### 2.1 Absolute maximum ratings

Stressing the device above the rating listed in [Table 3](#) may cause permanent damage to the device. These are stress ratings only and operation of the device at these or any other conditions above those indicated in the operating sections of this specification is not implied. Exposure to the conditions in table below for extended periods may affect device reliability.

Table 3. Absolute maximum ratings

Symbol	Parameter	Value	Unit
$V_{CC}$	DC supply voltage	38	V
$-V_{CC}$	Reverse DC supply voltage	16	
$V_{CCPK}$	Maximum transient supply voltage (ISO7637-2:2004 Pulse 5b level IV clamped to 40 V; $R_L = 4 \Omega$ )	40	
$V_{CCJS}$	Maximum jump start voltage for single pulse short circuit protection	28	
$-I_{GND}$	DC reverse ground pin current	200	mA
$I_{OUT}$	OUTPUT <sub>0,1</sub> DC output current	Internally limited	A
$-I_{OUT}$	Reverse DC output current	22	
$I_{IN}$	INPUT <sub>0,1</sub> DC input current	-1 to 10	mA
$I_{SEn}$	SE <sub>n</sub> DC input current		
$I_{SEL}$	SEL <sub>0,1</sub> DC input current		
$I_{FR}$	FaultRST DC input current		



Table 3. Absolute maximum ratings (continued)

Symbol	Parameter	Value	Unit
$V_{FR}$	FaultRST DC input voltage	7.5	V
$I_{SENSE}$	MultiSense pin DC output current ( $V_{GND} = V_{CC}$ and $V_{SENSE} < 0$ V)	10	mA
	MultiSense pin DC output current in reverse ( $V_{CC} < 0$ V)	-20	
$E_{MAX}$	Maximum switching energy (single pulse) ( $T_{DEMAG} = 0.4$ ms; $T_{jstart} = 150^{\circ}C$ )	144	mJ
$V_{ESD}$	Electrostatic discharge (JEDEC 22 A-114 F)		
	– INPUT <sub>0,1</sub>	4000	V
	– MultiSense	2000	V
	– SEn, SEL <sub>0,1</sub> , FaultRST	4000	V
	– OUTPUT <sub>0,1</sub>	4000	V
	– V <sub>CC</sub>	4000	V
$V_{ESD}$	Charge device model (CDM-AEC-Q100-011)	750	V
$T_j$	Junction operating temperature	-40 to 150	°C
$T_{stg}$	Storage temperature	-55 to 150	

## 2.2 Thermal data

Table 4. Thermal data

Symbol	Parameter	Typ. value	Unit
$R_{thj-board}$	Thermal resistance junction-board (JEDEC JESD 51-5 / 51-8) <sup>(1)(2)</sup>	4	°C/W
$R_{thj-amb}$	Thermal resistance junction-ambient (JEDEC JESD 51-5) <sup>(1)(3)</sup>	50.6	
$R_{thj-amb}$	Thermal resistance junction-ambient (JEDEC JESD 51-7) <sup>(1)(2)</sup>	16.6	

1. One channel ON.
2. Device mounted on four-layers 2s2p PCB
3. Device mounted on two-layers 2s0p PCB with 2 cm<sup>2</sup> heatsink copper trace

## 2.3 Main electrical characteristics

$7\text{ V} < V_{CC} < 28\text{ V}$ ;  $-40^\circ\text{C} < T_j < 150^\circ\text{C}$ , unless otherwise specified.

All typical values refer to  $V_{CC} = 13\text{ V}$ ;  $T_j = 25^\circ\text{C}$ , unless otherwise specified.

**Table 5. Power section**

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$V_{CC}$	Operating supply voltage		4	13	28	V
$V_{USD}$	Undervoltage shutdown				4	
$V_{USDReset}$	Undervoltage shutdown reset				5	
$V_{USDhyst}$	Undervoltage shutdown hysteresis			0.3		
$R_{ON}$	On-state resistance <sup>(1)</sup>	$I_{OUT} = 7\text{ A}$ ; $T_j = 25^\circ\text{C}$		12		mΩ
		$I_{OUT} = 7\text{ A}$ ; $T_j = 150^\circ\text{C}$			24	
		$I_{OUT} = 7\text{ A}$ ; $V_{CC} = 4\text{ V}$ ; $T_j = 25^\circ\text{C}$				
$R_{ON\_REV}$	On-state resistance in reverse battery	$I_{OUT} = -7\text{ A}$ ; $V_{CC} = -13\text{ V}$ ; $T_j = 25^\circ\text{C}$		12		mΩ
$V_{clamp}$	Clamp voltage	$I_S = 20\text{ mA}$ ; $25^\circ\text{C} < T_j < 150^\circ\text{C}$	41	46	52	V
		$I_S = 20\text{ mA}$ ; $T_j = -40^\circ\text{C}$	38			V
$I_{STBY}$	Supply current in standby at $V_{CC} = 13\text{ V}$ <sup>(2)</sup>	$V_{CC} = 13\text{ V}$ ; $V_{IN0,1} = V_{OUT0,1} = V_{FR} = V_{SEn} = 0\text{ V}$ ; $V_{SEL0,1} = 0\text{ V}$ ; $T_j = 25^\circ\text{C}$			0.5	μA
		$V_{CC} = 13\text{ V}$ ; $V_{IN0,1} = V_{OUT0,1} = V_{FR} = V_{SEn} = 0\text{ V}$ ; $V_{SEL0,1} = 0\text{ V}$ ; $T_j = 85^\circ\text{C}$ <sup>(3)</sup>			0.5	μA
		$V_{CC} = 13\text{ V}$ ; $V_{IN0,1} = V_{OUT0,1} = V_{FR} = V_{SEn} = 0\text{ V}$ ; $V_{SEL0,1} = 0\text{ V}$ ; $T_j = 125^\circ\text{C}$				3
$t_{D\_STBY}$	Standby mode blanking time	$V_{CC} = 13\text{ V}$ ; $V_{IN0,1} = V_{OUT0,1} = 0\text{ V}$ ; $V_{FR} = V_{SEL0,1} = 0\text{ V}$ ; $V_{SEn} = 5\text{ V}$ to $0\text{ V}$	60	300	550	μs
$I_{S(ON)}$	Supply current	$V_{CC} = 13\text{ V}$ ; $V_{SEn} = V_{FR} = V_{SEL0,1} = 0\text{ V}$ ; $V_{IN0,1} = 5\text{ V}$ ; $I_{OUT0} = 0\text{ A}$ ; $I_{OUT1} = 0\text{ A}$		5	8	mA
$I_{GND(ON)}$	Control stage current consumption in ON state. All channels active.	$V_{CC} = 13\text{ V}$ ; $V_{SEn} = 5\text{ V}$ ; $V_{FR} = V_{SEL0,1} = 0\text{ V}$ ; $V_{IN0,1} = 5\text{ V}$ ; $I_{OUT0} = 7\text{ A}$ ; $I_{OUT1} = 7\text{ A}$			10	mA

Table 5. Power section

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$I_{L(off)}$	Off-state output current at $V_{CC} = 13\text{ V}$ <sup>(1)</sup>	$V_{IN0,1} = V_{OUT0,1} = 0\text{ V}$ ; $V_{CC} = 13\text{ V}$ ; $T_j = 25^\circ\text{C}$	0	0.01	0.5	$\mu\text{A}$
		$V_{IN0,1} = V_{OUT0,1} = 0\text{ V}$ ; $V_{CC} = 13\text{ V}$ ; $T_j = 125^\circ\text{C}$	0		3	
$V_F$	Output - $V_{CC}$ diode voltage <sup>(1)</sup>	$I_{OUT} = -7\text{ A}$ ; $T_j = 150^\circ\text{C}$			0.7	V

1. For each channel.
2. PowerMOS leakage included.
3. Parameter specified by design; not subject to production test.

Table 6. Switching ( $V_{CC} = 13\text{ V}$ ;  $-40^\circ\text{C} < T_j < 150^\circ\text{C}$ , unless otherwise specified)<sup>(1)</sup>

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$t_{d(on)}$	Turn-on delay time at $T_j = 25^\circ\text{C}$	$R_L = 1.84\ \Omega$	10	50	120	$\mu\text{s}$
$t_{d(off)}$	Turn-off delay time at $T_j = 25^\circ\text{C}$		10	45	100	
$(dV_{OUT}/dt)_{on}$	Turn-on voltage slope at $T_j = 25^\circ\text{C}$	$R_L = 1.84\ \Omega$	0.1	0.45	0.7	V/ $\mu\text{s}$
$(dV_{OUT}/dt)_{off}$	Turn-off voltage slope at $T_j = 25^\circ\text{C}$		0.2	0.5	0.8	
$W_{ON}$	Switching energy losses at turn-on ( $t_{won}$ )	$R_L = 1.84\ \Omega$	—	0.6	1.4 <sup>(2)</sup>	mJ
$W_{OFF}$	Switching energy losses at turn-off ( $t_{woff}$ )	$R_L = 1.84\ \Omega$	—	0.6	1.3 <sup>(2)</sup>	mJ
$t_{SKEW}$	Differential pulse skew ( $t_{PHL} - t_{PLH}$ ) see <a href="#">Figure 6</a>	$R_L = 1.84\ \Omega$	-60	-10	40	$\mu\text{s}$

1. See [Figure 6: Switching times and Pulse skew](#).
2. Parameter guaranteed by design and characterization, not subject to production test.

Table 7. Logic Inputs ( $7\text{ V} < V_{CC} < 28\text{ V}$ ;  $-40^\circ\text{C} < T_j < 150^\circ\text{C}$ )

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
<b>INPUT<sub>0,1</sub> characteristics</b>						
$V_{IL}$	Input low level voltage				0.9	V
$I_{IL}$	Low level input current	$V_{IN} = 0.9\text{ V}$	1			$\mu\text{A}$
$V_{IH}$	Input high level voltage		2.1			V
$I_{IH}$	High level input current	$V_{IN} = 2.1\text{ V}$			10	$\mu\text{A}$
$V_{I(hyst)}$	Input hysteresis voltage		0.2			V
$V_{ICL}$	Input clamp voltage	$I_{IN} = 1\text{ mA}$	5.3		7.2	V
		$I_{IN} = -1\text{ mA}$		-0.7		
<b>FaultRST characteristics</b>						
$V_{FRL}$	Input low level voltage				0.9	V

**Table 7. Logic Inputs (7 V < V<sub>CC</sub> < 28 V; -40°C < T<sub>j</sub> < 150°C) (continued)**

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
I <sub>FRL</sub>	Low level input current	V <sub>IN</sub> = 0.9 V	1			μA
V <sub>FRH</sub>	Input high level voltage		2.1			V
I <sub>FRH</sub>	High level input current	V <sub>IN</sub> = 2.1 V			10	μA
V <sub>FR(hyst)</sub>	Input hysteresis voltage		0.2			V
V <sub>FRCL</sub>	Input clamp voltage	I <sub>IN</sub> = 1 mA	5.3		7.5	V
		I <sub>IN</sub> = -1 mA		-0.7		
<b>SEL<sub>0,1</sub> characteristics (7 V &lt; V<sub>CC</sub> &lt; 18 V)</b>						
V <sub>SELL</sub>	Input low level voltage				0.9	V
I <sub>SELL</sub>	Low level input current	V <sub>IN</sub> = 0.9 V	1			μA
V <sub>SELH</sub>	Input high level voltage		2.1			V
I <sub>SELH</sub>	High level input current	V <sub>IN</sub> = 2.1 V			10	μA
V <sub>SEL(hyst)</sub>	Input hysteresis voltage		0.2			V
V <sub>SELCL</sub>	Input clamp voltage	I <sub>IN</sub> = 1 mA	5.3		7.2	V
		I <sub>IN</sub> = -1 mA		-0.7		
<b>SEn characteristics (7 V &lt; V<sub>CC</sub> &lt; 18 V)</b>						
V <sub>SEnL</sub>	Input low level voltage				0.9	V
I <sub>SEnL</sub>	Low level input current	V <sub>IN</sub> = 0.9 V	1			μA
V <sub>SEnH</sub>	Input high level voltage		2.1			V
I <sub>SEnH</sub>	High level input current	V <sub>IN</sub> = 2.1 V			10	μA
V <sub>SEn(hyst)</sub>	Input hysteresis voltage		0.2			V
V <sub>SEnCL</sub>	Input clamp voltage	I <sub>IN</sub> = 1 mA	5.3		7.2	V
		I <sub>IN</sub> = -1 mA		-0.7		

**Table 8. Protections (7 V < V<sub>CC</sub> < 18 V; -40°C < T<sub>j</sub> < 150°C)**

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
I <sub>LIMH</sub> <sup>(1)</sup>	DC short circuit current	V <sub>CC</sub> = 13 V	60	75	96	A
		4 V < V <sub>CC</sub> < 18 V <sup>(2)</sup>			96	
I <sub>LIML</sub>	Short circuit current during thermal cycling	V <sub>CC</sub> = 13 V; T <sub>R</sub> < T <sub>j</sub> < T <sub>TSD</sub>		25		
T <sub>TSD</sub>	Shutdown temperature		150	175	200	°C
T <sub>R</sub>	Reset temperature <sup>(2)</sup>		T <sub>RS</sub> + 1	T <sub>RS</sub> + 5		
T <sub>RS</sub>	Thermal reset of fault diagnostic indication	V <sub>FR</sub> = 0 V; V <sub>SEn</sub> = 5 V	135			
T <sub>HYST</sub>	Thermal hysteresis (T <sub>TSD</sub> - T <sub>R</sub> ) <sup>(2)</sup>			5		

Table 8. Protections (7 V < V<sub>CC</sub> < 18 V; -40°C < T<sub>j</sub> < 150°C) (continued)

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$\Delta T_{J\_SD}$	Dynamic temperature			60		K
$t_{LATCH\_RST}$	Fault reset time for output unlatch <sup>(2)</sup>	V <sub>FR</sub> = 5 V to 0 V; V <sub>SEn</sub> = 5 V; V <sub>IN0,1</sub> = 5 V; V <sub>SEL0,1</sub> = 0 V	3	10	20	μs
V <sub>DEMAG</sub>	Turn-off output voltage clamp	I <sub>OUT</sub> = 2 A; L = 6 mH; T <sub>j</sub> = -40 °C	V <sub>CC</sub> - 38			V
		I <sub>OUT</sub> = 2 A; L = 6 mH; T <sub>j</sub> = 25°C to 150°C	V <sub>CC</sub> - 41	V <sub>CC</sub> - 46	V <sub>CC</sub> - 52	
V <sub>ON</sub>	Output voltage drop limitation	I <sub>OUT</sub> = 0.7 A		20		mV

1. Parameter guaranteed by an indirect test sequence.
2. Parameter guaranteed by design and characterization; not subject to production test.

Table 9. MultiSense (7 V < V<sub>CC</sub> < 18 V; -40°C < T<sub>j</sub> < 150°C)

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
V <sub>SENSE\_CL</sub>	MultiSense clamp voltage	V <sub>SEn</sub> = 0 V; I <sub>SENSE</sub> = 1 mA	-17		-12	V
		V <sub>SEn</sub> = 0 V; I <sub>SENSE</sub> = -1 mA		7		V
<b>Current Sense characteristics</b>						
K <sub>OL</sub>	I <sub>OUT</sub> /I <sub>SENSE</sub>	I <sub>OUT</sub> = 10 mA; V <sub>SENSE</sub> = 0.5 V; V <sub>SEn</sub> = 5 V	1400			
dK <sub>cal</sub> /K <sub>cal</sub> <sup>(1)(2)</sup>	Current sense ratio drift at calibration point	I <sub>CAL</sub> = 130 mA; I <sub>OUT</sub> = 10 mA to 250 mA; V <sub>SENSE</sub> = 0.5 V; V <sub>SEn</sub> = 5 V	-35		35	%
K <sub>LED</sub>	I <sub>OUT</sub> /I <sub>SENSE</sub>	I <sub>OUT</sub> = 250 mA; V <sub>SENSE</sub> = 0.5 V; V <sub>SEn</sub> = 5 V	2490	5100	8000	
K <sub>0</sub>	I <sub>OUT</sub> /I <sub>SENSE</sub>	I <sub>OUT</sub> = 0.7 A; V <sub>SENSE</sub> = 0.5 V; V <sub>SEn</sub> = 5 V	2560	5120	7680	
dK <sub>0</sub> /K <sub>0</sub> <sup>(1)(2)</sup>	Current sense ratio drift	I <sub>OUT</sub> = 0.7 A; V <sub>SENSE</sub> = 0.5 V; V <sub>SEn</sub> = 5 V	-25		25	%
K <sub>1</sub>	I <sub>OUT</sub> /I <sub>SENSE</sub>	I <sub>OUT</sub> = 1.4 A; V <sub>SENSE</sub> = 4 V; V <sub>SEn</sub> = 5 V	3480	4900	6470	
dK <sub>1</sub> /K <sub>1</sub> <sup>(1)(2)</sup>	Current sense ratio drift	I <sub>OUT</sub> = 1.4 A; V <sub>SENSE</sub> = 4 V; V <sub>SEn</sub> = 5 V	-20		20	%
K <sub>2</sub>	I <sub>OUT</sub> /I <sub>SENSE</sub>	I <sub>OUT</sub> = 7 A; V <sub>SENSE</sub> = 4 V; V <sub>SEn</sub> = 5 V	3410	4280	5120	
dK <sub>2</sub> /K <sub>2</sub> <sup>(1)(2)</sup>	Current sense ratio drift	I <sub>OUT</sub> = 7 A; V <sub>SENSE</sub> = 4 V; V <sub>SEn</sub> = 5 V	-10		10	%
K <sub>3</sub>	I <sub>OUT</sub> /I <sub>SENSE</sub>	I <sub>OUT</sub> = 21 A; V <sub>SENSE</sub> = 4 V; V <sub>SEn</sub> = 5 V	3810	4300	4660	
dK <sub>3</sub> /K <sub>3</sub> <sup>(1)(2)</sup>	Current sense ratio drift	I <sub>OUT</sub> = 21 A; V <sub>SENSE</sub> = 4 V; V <sub>SEn</sub> = 5 V	-5		5	%

Table 9. MultiSense (7 V < V<sub>CC</sub> < 18 V; -40°C < T<sub>j</sub> < 150°C) (continued)

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
I <sub>SENSE0</sub>	MultiSense leakage current	MultiSense disabled: V <sub>SEn</sub> = 0 V;	0		0.5	μA
		MultiSense disabled: -1 V < V <sub>SENSE</sub> < 5 V <sup>(1)</sup>	-0.5		0.5	μA
		MultiSense enabled: V <sub>SEn</sub> = 5 V; All channel ON; I <sub>OUTX</sub> = 0 A; Ch <sub>X</sub> diagnostic selected; – E.g. Ch <sub>0</sub> : V <sub>IN0</sub> = 5 V; V <sub>IN1</sub> = 5 V; V <sub>SEL0</sub> = 0 V; V <sub>SEL1</sub> = 0 V; I <sub>OUT0</sub> = 0 A; I <sub>OUT1</sub> = 7 A	0		2	μA
		MultiSense enabled: V <sub>SEn</sub> = 5 V; Ch <sub>X</sub> channel OFF; Ch <sub>X</sub> diagnostic selected; – E.g. Ch <sub>0</sub> : V <sub>IN0</sub> = 0 V; V <sub>IN1</sub> = 5 V; V <sub>SEL0</sub> = 0 V; V <sub>SEL1</sub> = 0 V; I <sub>OUT1</sub> = 7 A	0		2	μA
V <sub>OUT_MSD</sub> <sup>(1)</sup>	Output Voltage for MultiSense shutdown	V <sub>SEn</sub> = 5 V; R <sub>SENSE</sub> = 2.7 kΩ – E.g. Ch <sub>0</sub> : V <sub>IN0</sub> = 5 V; V <sub>SEL0</sub> = 0 V; V <sub>SEL1</sub> = 0 V; I <sub>OUT0</sub> = 7 A		5		V
V <sub>SENSE_SAT</sub>	Multisense saturation voltage	V <sub>CC</sub> = 7 V; R <sub>SENSE</sub> = 2.7 K; V <sub>SEn</sub> = 5 V; V <sub>IN0</sub> = 5 V; V <sub>SEL0,1</sub> = 0 V; I <sub>OUT0</sub> = 21 A; T <sub>j</sub> = 150°C	5			V
I <sub>SENSE_SAT</sub> <sup>(1)</sup>	CS saturation current	V <sub>CC</sub> = 7 V; V <sub>SENSE</sub> = 4 V; V <sub>SEn</sub> = 5 V; V <sub>IN0</sub> = 5 V; V <sub>SEL0,1</sub> = 0 V; T <sub>j</sub> = 150°C	4			mA
I <sub>OUT_SAT</sub> <sup>(1)</sup>	Output saturation current	V <sub>CC</sub> = 7 V; V <sub>SENSE</sub> = 4 V; V <sub>IN0</sub> = 5 V; V <sub>SEn</sub> = 5 V; V <sub>SEL0,1</sub> = 0 V; T <sub>j</sub> = 150°C	23			A
<b>Off-state diagnostic</b>						
V <sub>OL</sub>	Off-state open-load voltage detection threshold	V <sub>SEn</sub> = 5 V; Ch <sub>X</sub> OFF; Ch <sub>X</sub> diagnostic selected – E.g. Ch <sub>0</sub> V <sub>IN0</sub> = 0 V; V <sub>SEL0</sub> = 0 V; V <sub>SEL1</sub> = 0 V;	2	3	4	V
I <sub>L(off2)</sub>	OFF state output sink current	V <sub>IN</sub> = 0 V; V <sub>OUT</sub> = V <sub>OL</sub> ; T <sub>j</sub> = -40°C to 125°C	-100		-15	μA

Table 9. MultiSense (7 V < V<sub>CC</sub> < 18 V; -40°C < T<sub>j</sub> < 150°C) (continued)

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
t <sub>DSTKON</sub>	Off-state diagnostic delay time from falling edge of INPUT (see XXX)	V <sub>SEn</sub> = 5 V; Ch <sub>X</sub> ON to OFF transition Ch <sub>X</sub> diagnostic selected – E.g: Ch <sub>0</sub> V <sub>IN0</sub> = 5 V to 0 V; V <sub>SELO</sub> = 0 V; V <sub>SEL1</sub> = 0 V; I <sub>OUT0</sub> = 0 A; V <sub>OUT</sub> = 4 V	100	350	700	μs
t <sub>D_OL_V</sub>	Settling time for valid OFF-state open load diagnostic indication from rising edge of SE <sub>n</sub>	V <sub>IN0</sub> = 0 V; V <sub>IN1</sub> = 0 V; V <sub>FR</sub> = 0 V; V <sub>SELO</sub> = 0 V; V <sub>SEL1</sub> = 0 V; V <sub>OUT0</sub> = 4 V; V <sub>SEn</sub> = 0 V to 5 V			60	μs
t <sub>D_VOL</sub>	Off-state diagnostic delay time from rising edge of V <sub>OUT</sub>	V <sub>SEn</sub> = 5 V; Ch <sub>X</sub> OFF Ch <sub>X</sub> diagnostic selected – E.g: Ch <sub>0</sub> V <sub>IN0</sub> = 0 V; V <sub>SELO</sub> = 0 V; V <sub>SEL1</sub> = 0 V; V <sub>OUT</sub> = 0 V to 4 V		5	30	μs
<b>Chip temperature analog feedback</b>						
V <sub>SENSE_TC</sub>	MultiSense output voltage proportional to chip temperature	V <sub>SEn</sub> = 5 V; V <sub>SELO</sub> = 0 V; V <sub>SEL1</sub> = 5 V; V <sub>IN0,1</sub> = 0 V; R <sub>SENSE</sub> = 1 kΩ; T <sub>j</sub> = -40°C	2.325	2.41	2.495	V
		V <sub>SEn</sub> = 5 V; V <sub>SELO</sub> = 0 V; V <sub>SEL1</sub> = 5 V; V <sub>IN0,1</sub> = 0 V; R <sub>SENSE</sub> = 1 kΩ; T <sub>j</sub> = 25°C	1.985	2.07	2.155	V
		V <sub>SEn</sub> = 5 V; V <sub>SELO</sub> = 0 V; V <sub>SEL1</sub> = 5 V; V <sub>IN0,1</sub> = 0 V; R <sub>SENSE</sub> = 1 kΩ; T <sub>j</sub> = 125°C	1.435	1.52	1.605	V
dV <sub>SENSE_TC</sub> /dT <sup>(1)</sup>	Temperature coefficient	T <sub>j</sub> = -40°C to 150°C		-5.5		mV/K
Transfer function		V <sub>SENSE_TC</sub> (T) = V <sub>SENSE_TC</sub> (T <sub>0</sub> ) + dV <sub>SENSE_TC</sub> / dT * (T - T <sub>0</sub> )				
<b>V<sub>CC</sub> supply voltage analog feedback</b>						
V <sub>SENSE_VCC</sub>	MultiSense output voltage proportional to V <sub>CC</sub> supply voltage	V <sub>CC</sub> = 13 V; V <sub>SEn</sub> = 5 V; V <sub>SELO</sub> = 5 V; V <sub>SEL1</sub> = 5 V; V <sub>IN0,1</sub> = 0 V; R <sub>SENSE</sub> = 1 kΩ	3.16	3.23	3.3	V
Transfer function <sup>(3)</sup>		V <sub>SENSE_VCC</sub> = V <sub>CC</sub> / 4				
<b>Fault diagnostic feedback (see Table 10)</b>						
V <sub>SENSEH</sub>	MultiSense output voltage in fault condition	V <sub>CC</sub> = 13 V; R <sub>SENSE</sub> = 1 kΩ – E.g: Ch <sub>0</sub> in open load V <sub>IN0</sub> = 0 V; V <sub>SEn</sub> = 5 V; V <sub>SELO</sub> = 0 V; V <sub>SEL1</sub> = 0 V; I <sub>OUT0</sub> = 0 A; V <sub>OUT</sub> = 4 V	5		6.6	V

Table 9. MultiSense (7 V < V<sub>CC</sub> < 18 V; -40°C < T<sub>j</sub> < 150°C) (continued)

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
I <sub>SENSEH</sub>	MultiSense output current in fault condition	V <sub>CC</sub> = 13 V; V <sub>SENSE</sub> = 5 V	7	20	30	mA
<b>MultiSense timings (current sense mode - see Figure 7)<sup>(4)</sup></b>						
t <sub>DSENSE1H</sub>	Current sense settling time from rising edge of SEn	V <sub>IN</sub> = 5 V; V <sub>SEn</sub> = 0 V to 5 V; R <sub>SENSE</sub> = 1 kΩ; R <sub>L</sub> = 1.84 Ω			60	μs
t <sub>DSENSE1L</sub>	Current sense disable delay time from falling edge of SEn	V <sub>IN</sub> = 5 V; V <sub>SEn</sub> = 5 V to 0 V; R <sub>SENSE</sub> = 1 kΩ; R <sub>L</sub> = 1.84 Ω		5	20	μs
t <sub>DSENSE2H</sub>	Current sense settling time from rising edge of INPUT	V <sub>IN</sub> = 0 V to 5 V; V <sub>SEn</sub> = 5 V; R <sub>SENSE</sub> = 1 kΩ; R <sub>L</sub> = 1.84 Ω		100	250	μs
Δt <sub>DSENSE2H</sub>	Current sense settling time from rising edge of I <sub>OUT</sub> (dynamic response to a step change of I <sub>OUT</sub> )	V <sub>IN</sub> = 5 V; V <sub>SEn</sub> = 5 V; R <sub>SENSE</sub> = 1 kΩ; R <sub>L</sub> = 1.84 Ω			100	μs
t <sub>DSENSE2L</sub>	Current sense turn-off delay time from falling edge of INPUT	V <sub>IN</sub> = 5 V to 0 V; V <sub>SEn</sub> = 5 V; R <sub>SENSE</sub> = 1 kΩ; R <sub>L</sub> = 1.84 Ω		50	250	μs
<b>MultiSense timings (chip temperature sense mode - see Figure 8)<sup>(4)</sup></b>						
t <sub>DSENSE3H</sub>	V <sub>SENSE_TC</sub> settling time from rising edge of SEn	V <sub>SEn</sub> = 0 V to 5 V; V <sub>SEL0</sub> = 0 V; V <sub>SEL1</sub> = 5 V; R <sub>SENSE</sub> = 1 kΩ			60	μs
t <sub>DSENSE3L</sub>	V <sub>SENSE_TC</sub> disable delay time from falling edge of SEn	V <sub>SEn</sub> = 5 V to 0 V; V <sub>SEL0</sub> = 0 V; V <sub>SEL1</sub> = 5 V; R <sub>SENSE</sub> = 1 kΩ			20	μs
<b>MultiSense timings (V<sub>CC</sub> voltage sense mode - see Figure 8)<sup>(4)</sup></b>						
t <sub>DSENSE4H</sub>	V <sub>SENSE_VCC</sub> settling time from rising edge of SEn	V <sub>SEn</sub> = 0 V to 5 V; V <sub>SEL0</sub> = 5 V; V <sub>SEL1</sub> = 5 V; R <sub>SENSE</sub> = 1 kΩ			60	μs
t <sub>DSENSE4L</sub>	V <sub>SENSE_VCC</sub> disable delay time from falling edge of SEn	V <sub>SEn</sub> = 5 V to 0 V; V <sub>SEL0</sub> = 5 V; V <sub>SEL1</sub> = 5 V; R <sub>SENSE</sub> = 1 kΩ			20	μs
<b>MultiSense timings (Multiplexer transition times)<sup>(4)</sup></b>						
t <sub>D_XtoY</sub>	MultiSense transition delay from Ch <sub>X</sub> to Ch <sub>Y</sub>	V <sub>IN0</sub> = 5 V; V <sub>IN1</sub> = 5 V; V <sub>SEn</sub> = 5 V; V <sub>SEL1</sub> = 0 V; V <sub>SEL0</sub> = 0 V to 5 V; I <sub>OUT0</sub> = 0A; I <sub>OUT1</sub> = 3 A; R <sub>SENSE</sub> = 1 kΩ			20	μs



Table 9. MultiSense (7 V < V<sub>CC</sub> < 18 V; -40°C < T<sub>j</sub> < 150°C) (continued)

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
t <sub>D_CS</sub> toTC	MultiSense transition delay from current sense to T <sub>C</sub> sense	V <sub>IN0</sub> = 5 V; V <sub>SEn</sub> = 5 V; V <sub>SEL0</sub> = 0 V; V <sub>SEL1</sub> = 0 V to 5 V; I <sub>OUT0</sub> = 3.5 A; R <sub>SENSE</sub> = 1 kΩ			60	μs
t <sub>D_TC</sub> toCS	MultiSense transition delay from T <sub>C</sub> sense to current sense	V <sub>IN0</sub> = 5 V; V <sub>SEn</sub> = 5 V; V <sub>SEL0</sub> = 0 V; V <sub>SEL1</sub> = 5 V to 0 V; I <sub>OUT0</sub> = 3.5 A; R <sub>SENSE</sub> = 1 kΩ			20	μs
t <sub>D_CS</sub> toVCC	MultiSense transition delay from current sense to V <sub>CC</sub> sense	V <sub>IN1</sub> = 5 V; V <sub>SEn</sub> = 5 V; V <sub>SEL0</sub> = 5 V; V <sub>SEL1</sub> = 0 V to 5 V; I <sub>OUT1</sub> = 3.5A; R <sub>SENSE</sub> = 1 kΩ			60	μs
t <sub>D_VCC</sub> toCS	MultiSense transition delay from V <sub>CC</sub> sense to current sense	V <sub>IN1</sub> = 5 V; V <sub>SEn</sub> = 5 V; V <sub>SEL0</sub> = 5 V; V <sub>SEL1</sub> = 5 V to 0 V; I <sub>OUT1</sub> = 3.5 A; R <sub>SENSE</sub> = 1 kΩ			20	μs
t <sub>D_TC</sub> toVCC	MultiSense transition delay from T <sub>C</sub> sense to V <sub>CC</sub> sense	V <sub>CC</sub> = 13 V; T <sub>j</sub> = 125°C; V <sub>SEn</sub> = 5 V; V <sub>SEL0</sub> = 0 V to 5 V; V <sub>SEL1</sub> = 5 V; R <sub>SENSE</sub> = 1 kΩ			20	μs
t <sub>D_VCC</sub> toTC	MultiSense transition delay from V <sub>CC</sub> sense to T <sub>C</sub> sense	V <sub>CC</sub> = 13 V; T <sub>j</sub> = 125°C; V <sub>SEn</sub> = 5 V; V <sub>SEL0</sub> = 5 V to 0 V; V <sub>SEL1</sub> = 5 V; R <sub>SENSE</sub> = 1 kΩ			20	μs
t <sub>D_CS</sub> toVSENSEH	MultiSense transition delay from stable current sense on Ch <sub>X</sub> to V <sub>SENSEH</sub> on Ch <sub>Y</sub>	V <sub>IN0</sub> = 5 V; V <sub>IN1</sub> = 0 V; V <sub>SEn</sub> = 5 V; V <sub>SEL1</sub> = 0 V; V <sub>SEL0</sub> = 0 V to 5 V; I <sub>OUT0</sub> = 7 A; V <sub>OUT1</sub> = 4 V; R <sub>SENSE</sub> = 1 kΩ			20	μs

1. Parameter specified by design; not subject to production test.
2. All values refer to V<sub>CC</sub> = 13 V; T<sub>j</sub> = 25 °C, unless otherwise specified.
3. V<sub>CC</sub> sensing and T<sub>C</sub> sensing are referred to GND potential.
4. Transition delay are measured up to +/- 10% of final conditions.

Figure 4.  $I_{OUT}/I_{SENSE}$  vs.  $I_{OUT}$

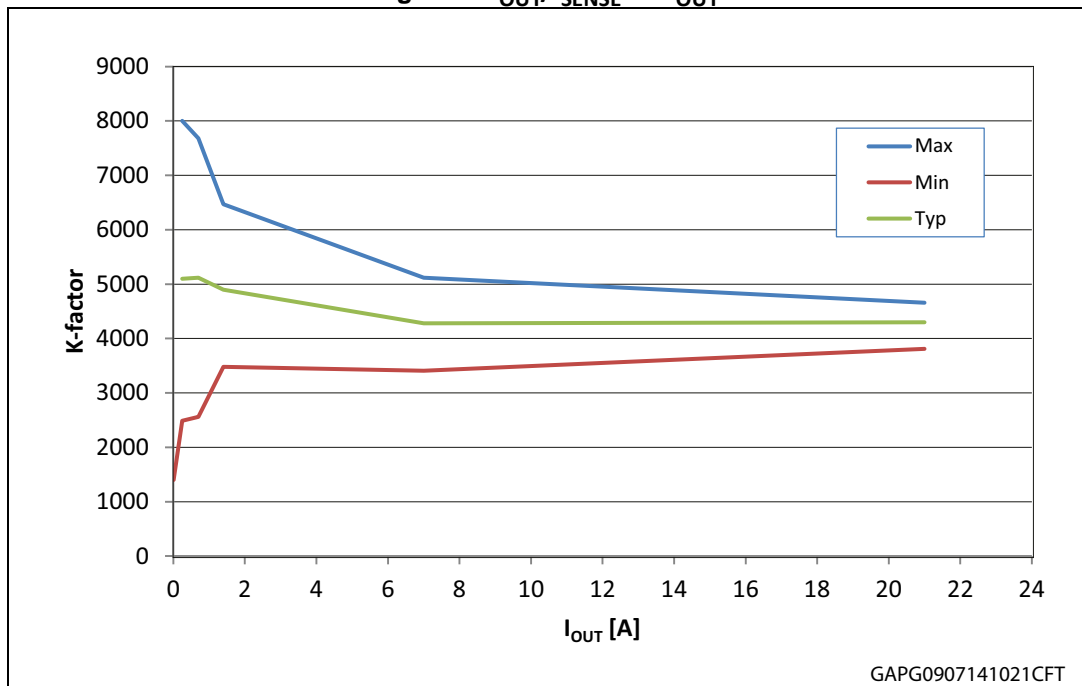


Figure 5. Current sense precision vs.  $I_{OUT}$

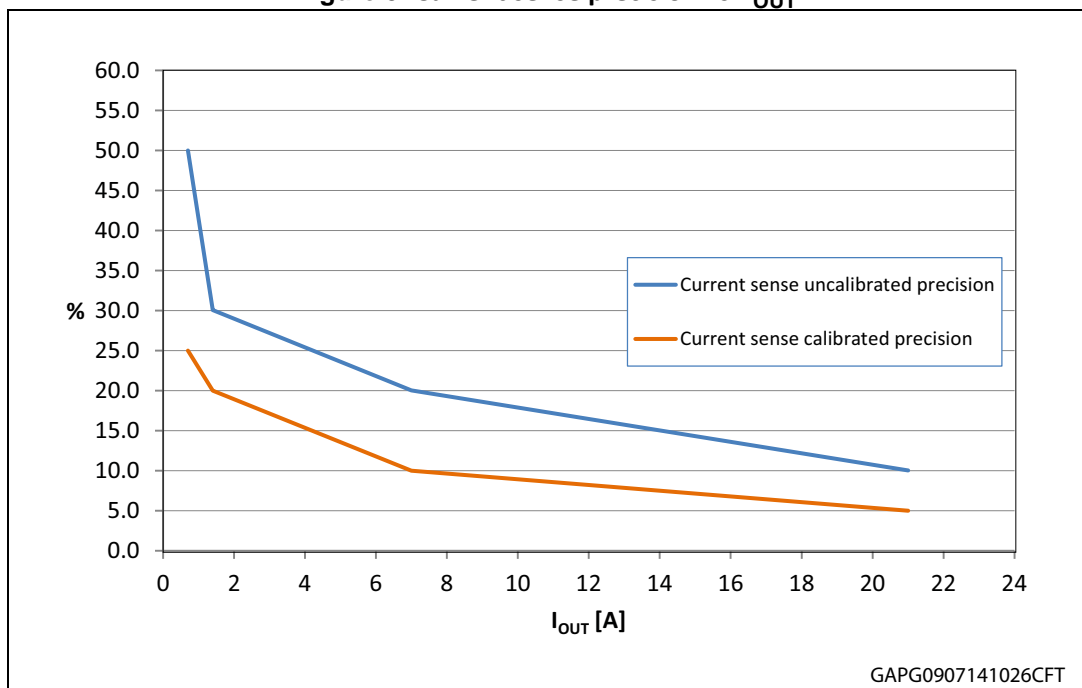


Figure 6. Switching times and Pulse skew

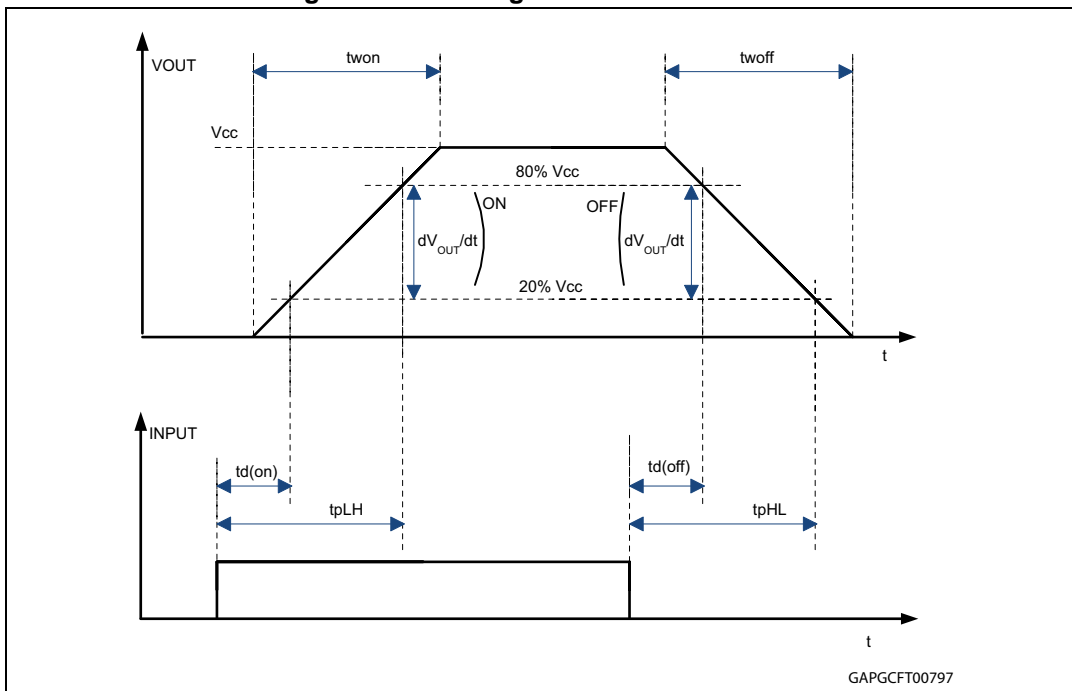


Figure 7. MultiSense timings (current sense mode)

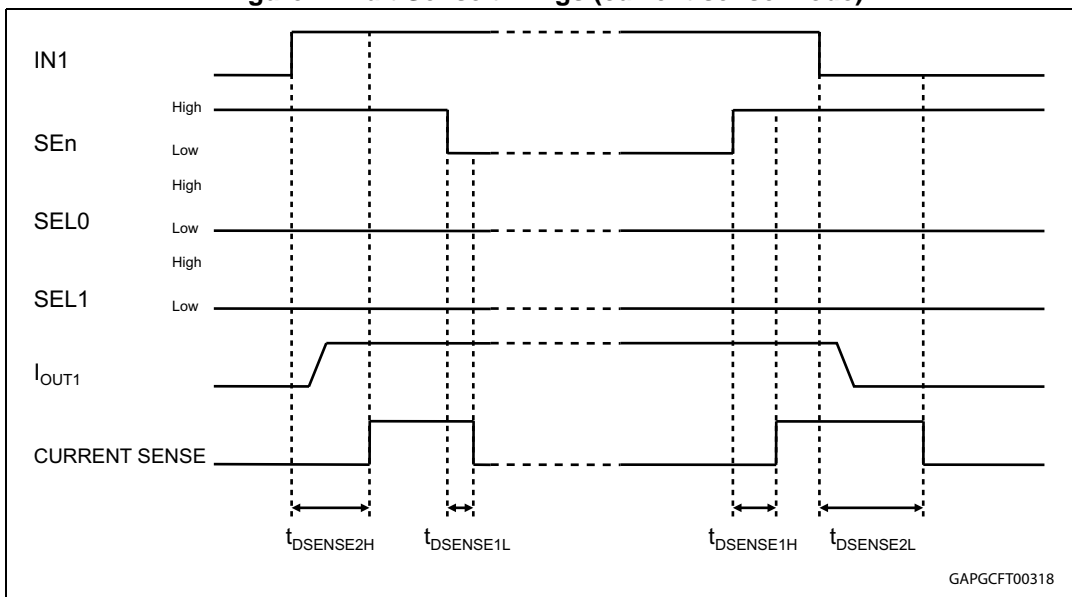


Figure 8. MultiSense timings (chip temperature and V<sub>CC</sub> sense mode)

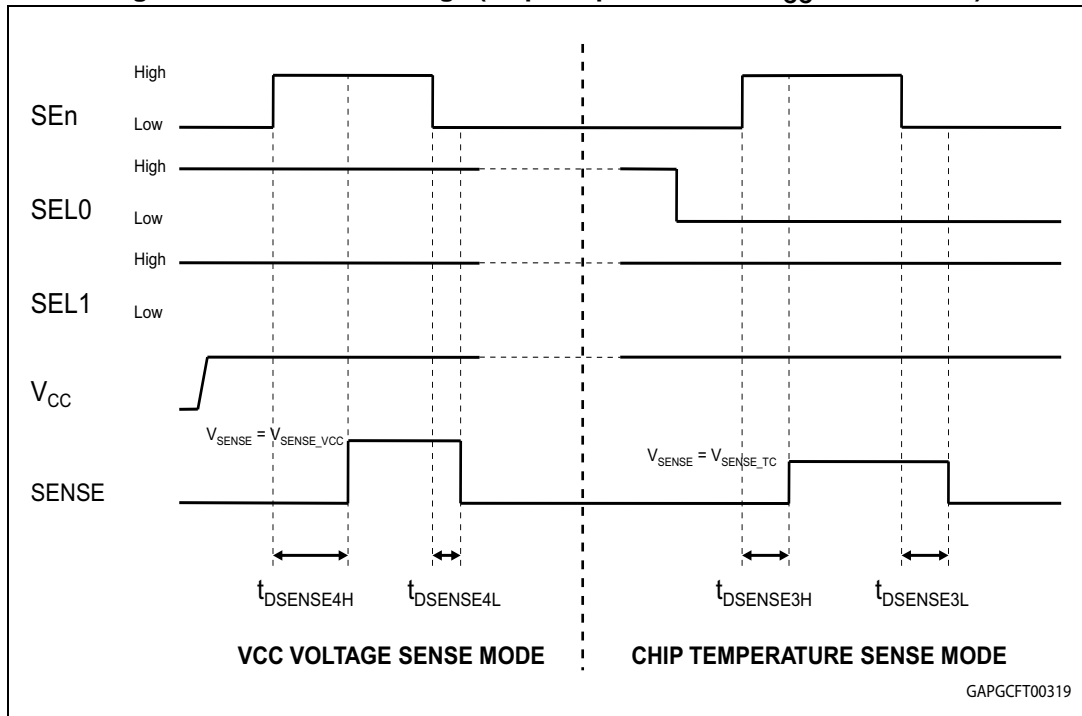


Figure 9. T<sub>DSTKON</sub>

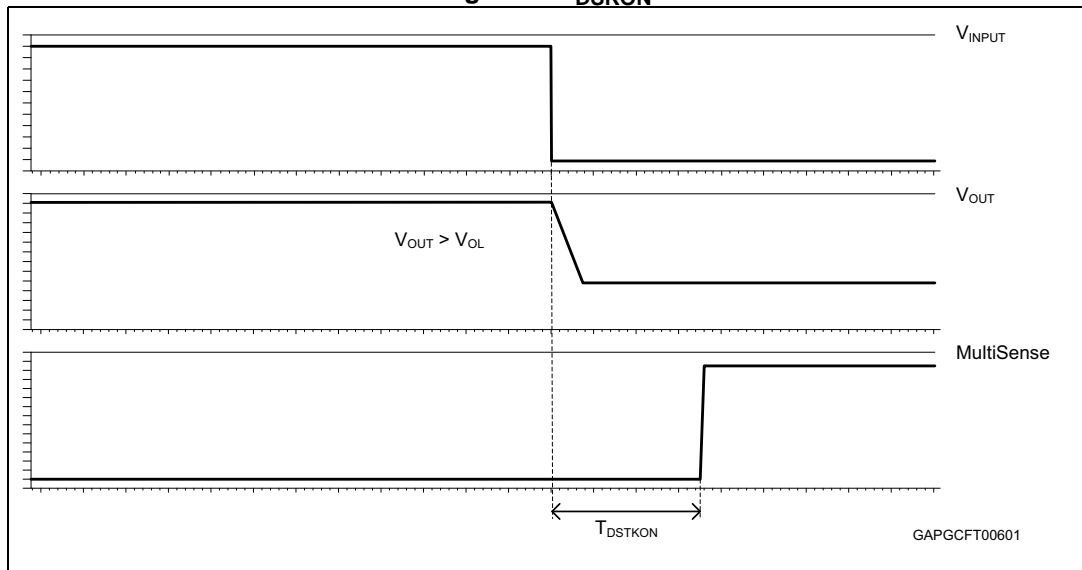


Table 10. Truth table

Mode	Conditions	IN <sub>x</sub>	FR	SEn	SEL <sub>x</sub>	OUT <sub>x</sub>	MultiSense	Comments
Standby	All logic inputs low	L	L	L	L	L	Hi-Z	Low quiescent current consumption
Normal	Nominal load connected; T <sub>j</sub> < 150°C	L	X	Refer to <a href="#">Table 11</a>		L	Refer to <a href="#">Table 11</a>	
		H	L			H		Outputs configured for auto-restart
		H	H			H		Outputs configured for latch off
Overload	Overload or short to GND causing: T <sub>j</sub> > T <sub>TSD</sub> or ΔT <sub>j</sub> > ΔT <sub>j_SD</sub>	L	X	Refer to <a href="#">Table 11</a>		L	Refer to <a href="#">Table 11</a>	
		H	L			H		Output cycles with temperature hysteresis
		H	H			L		Output latches off
Under-voltage	V <sub>CC</sub> < V <sub>USD</sub> (falling)	X	X	X	X	L L	Hi-Z Hi-Z	Re-start when V <sub>CC</sub> > V <sub>USD</sub> + V <sub>USDhyst</sub> (rising)
Off-state diagnostics	Short to V <sub>CC</sub>	L	X	Refer to <a href="#">Table 11</a>		H	Refer to <a href="#">Table 11</a>	
	Open-load	L	X			H		External pull up
Negative output voltage	Inductive loads turn-off	L	X	Refer to <a href="#">Table 11</a>		< 0 V	Refer to <a href="#">Table 11</a>	

Table 11. MultiSense multiplexer addressing

SEn	SEL <sub>1</sub>	SEL <sub>0</sub>	MUXchannel	MultiSense output			
				Normal mode	Overload	Off-state diag. <sup>(1)</sup>	Negative output
L	X	X		Hi-Z			
H	L	L	Channel 0 diagnostic	I <sub>SENSE</sub> = 1/K * I <sub>OUT0</sub>	V <sub>SENSE</sub> = V <sub>SENSEH</sub>	V <sub>SENSE</sub> = V <sub>SENSEH</sub>	Hi-Z
H	L	H	Channel 1 diagnostic	I <sub>SENSE</sub> = 1/K * I <sub>OUT1</sub>	V <sub>SENSE</sub> = V <sub>SENSEH</sub>	V <sub>SENSE</sub> = V <sub>SENSEH</sub>	Hi-Z
H	H	L	T <sub>CHIP</sub> Sense	V <sub>SENSE</sub> = V <sub>SENSE_TC</sub>			
H	H	H	V <sub>CC</sub> Sense	V <sub>SENSE</sub> = V <sub>SENSE_VCC</sub>			

1. In case the output channel corresponding to the selected MUX channel is latched off while the relevant input is low, Multisense pin delivers feedback according to OFF-State diagnostic.  
 Example 1: FR = 1; IN<sub>0</sub> = 0; OUT<sub>0</sub> = L (latched); MUX channel = channel 0 diagnostic; Mutisense = 0  
 Example 2: FR = 1; IN<sub>0</sub> = 0; OUT<sub>0</sub> = latched, V<sub>OUT0</sub> > V<sub>OL</sub>; MUX channel = channel 0 diagnostic; Mutisense = V<sub>SENSEH</sub>

## 2.4 Electrical characteristics curves

Figure 10. OFF-state output current

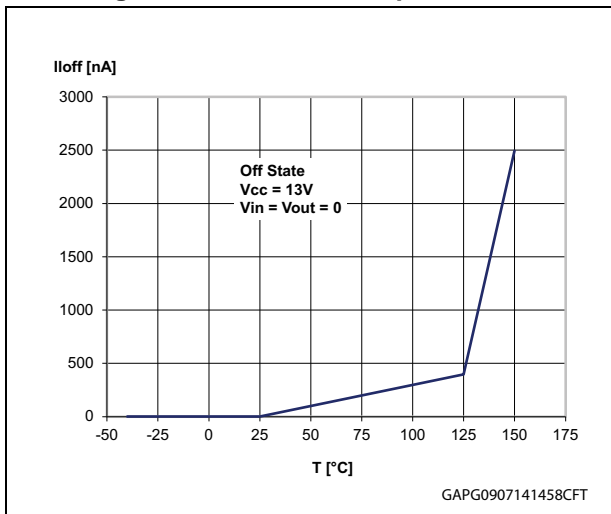


Figure 11. Standby current

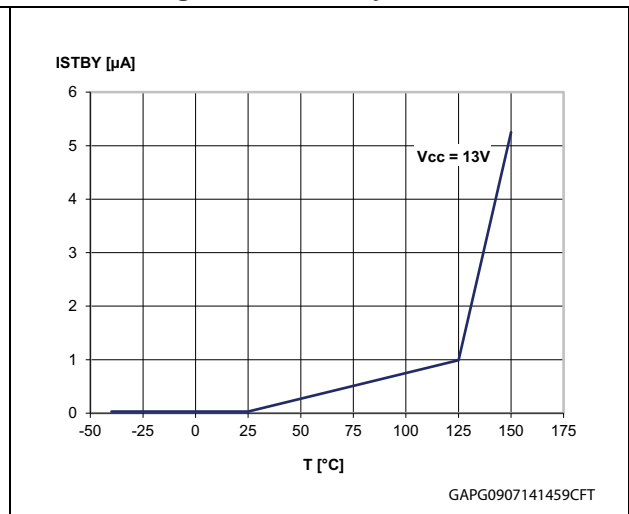


Figure 12. IGND(ON) vs. Iout

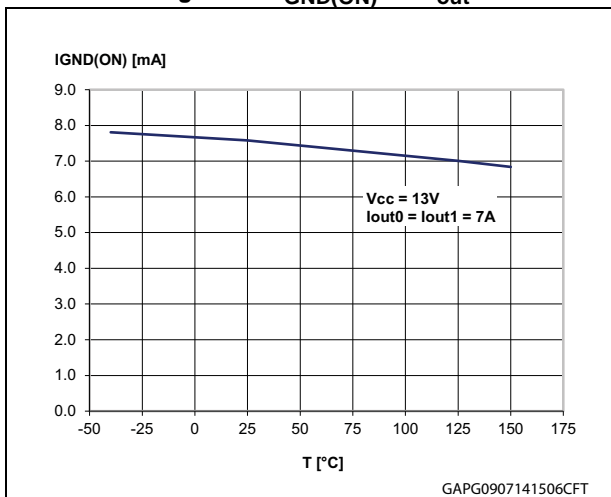


Figure 13. Logic Input high level voltage

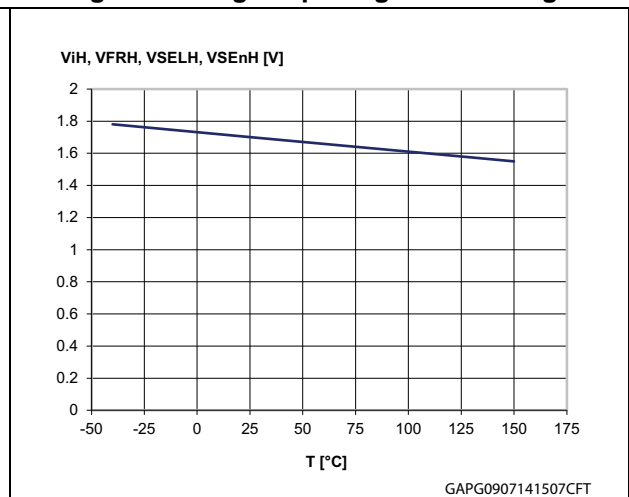


Figure 14. Logic Input low level voltage

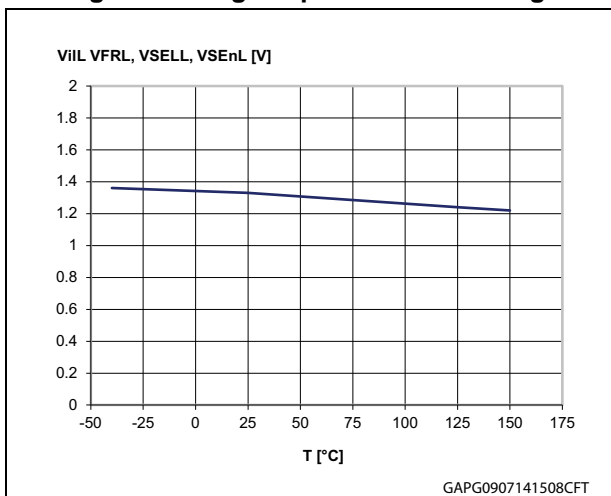


Figure 15. High level logic input current

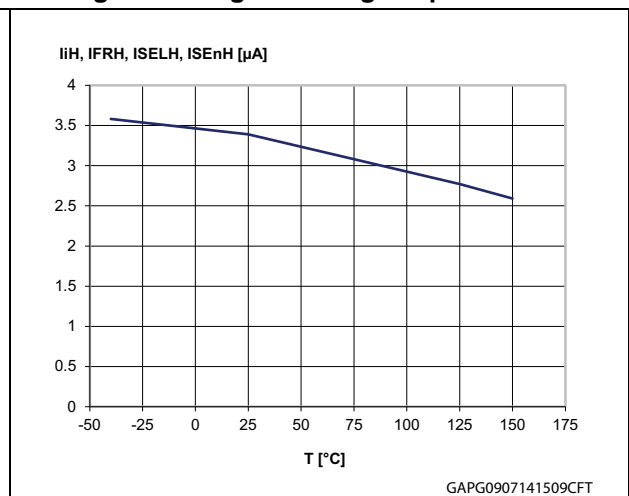


Figure 16. Low level logic input current

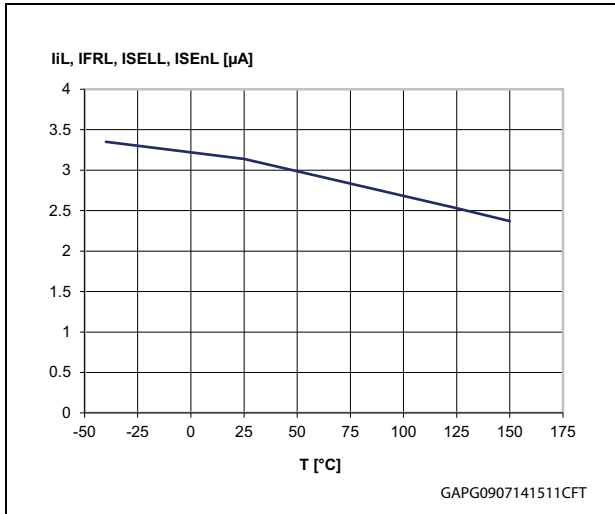


Figure 17. Logic Input hysteresis voltage

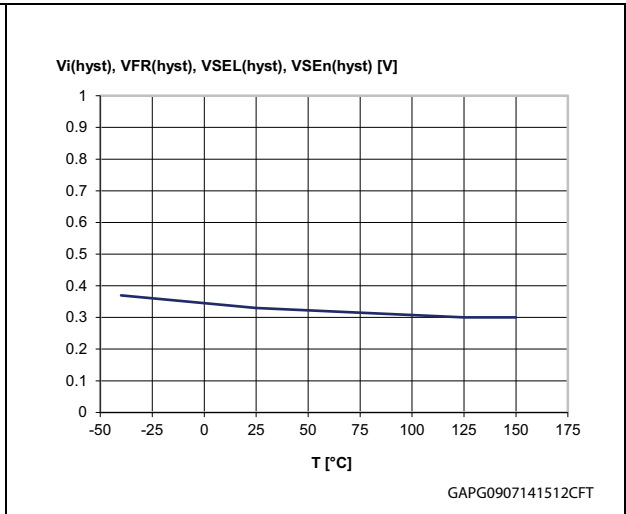


Figure 18. FaultRST Input clamp voltage

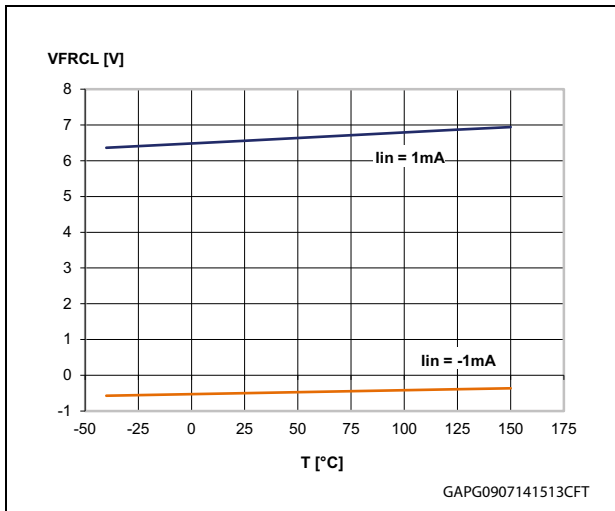


Figure 19. Undervoltage shutdown

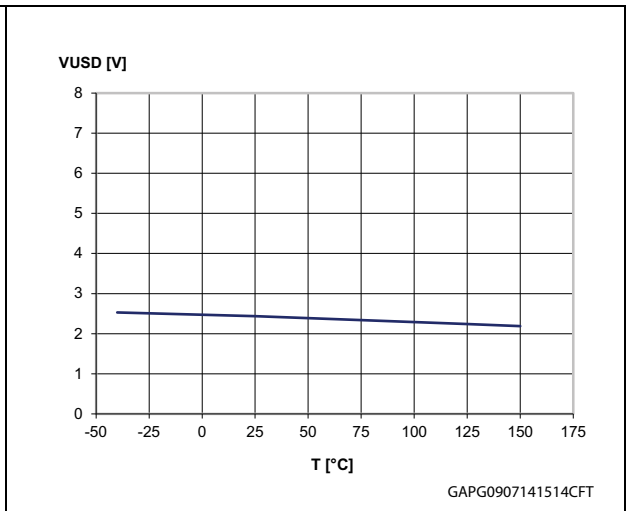


Figure 20. On-state resistance vs.  $T_{case}$

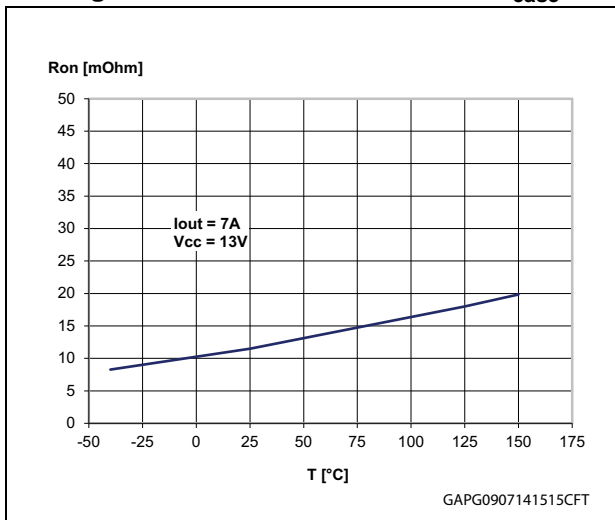


Figure 21. On-state resistance vs.  $V_{CC}$

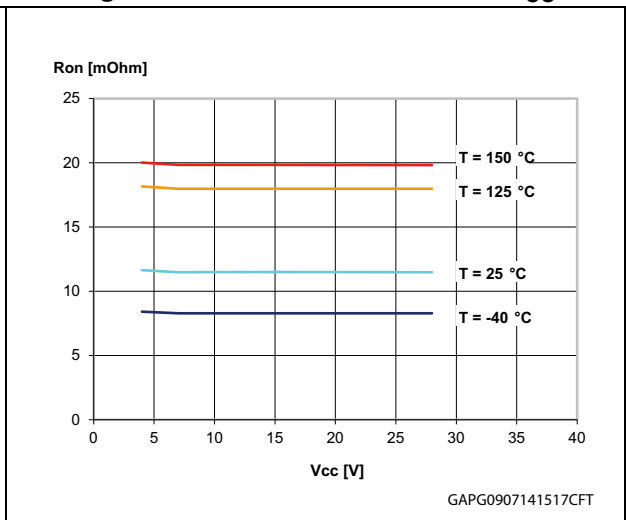


Figure 22. Turn-on voltage slope

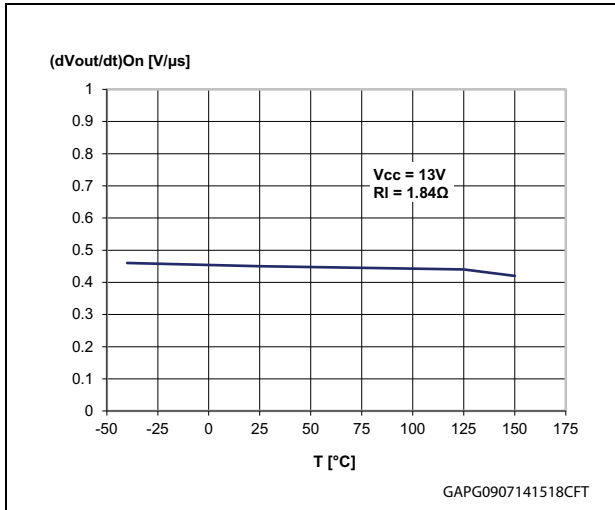


Figure 23. Turn-off voltage slope

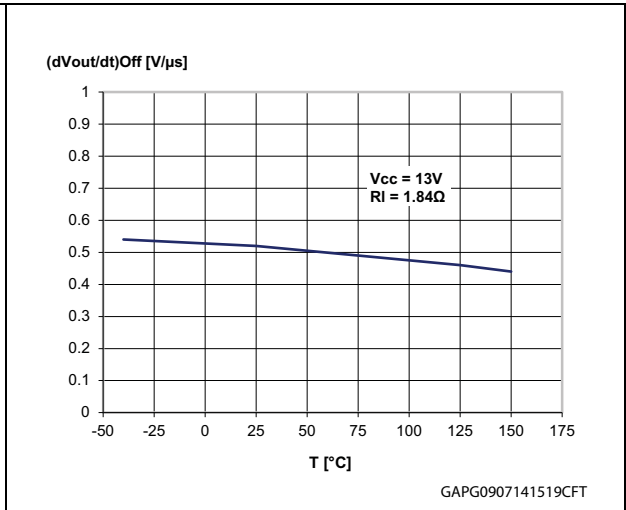


Figure 24. Won vs. T<sub>case</sub>

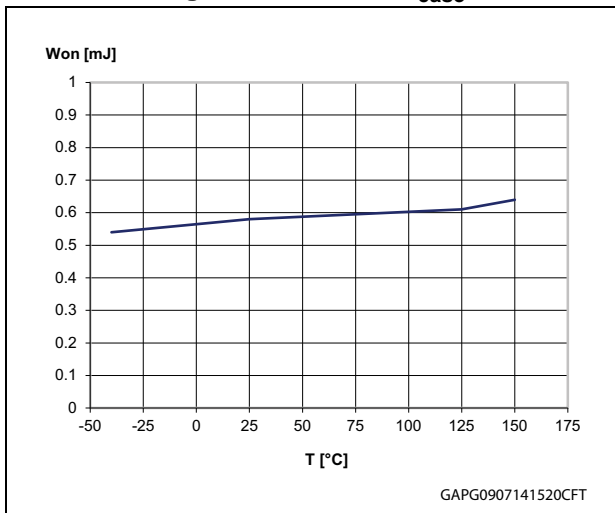


Figure 25. Woff vs. T<sub>case</sub>

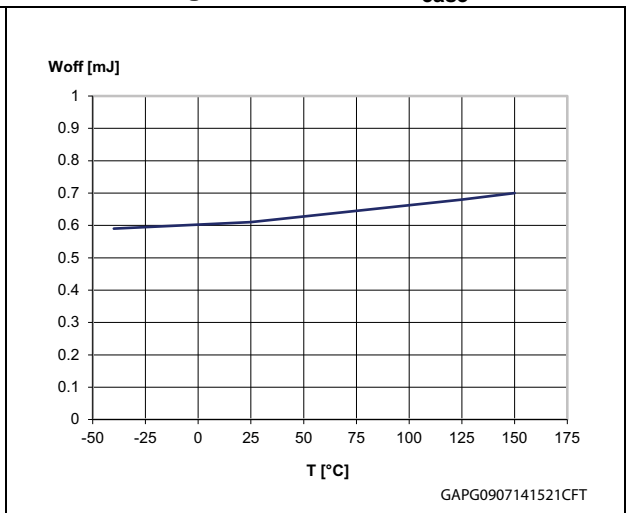


Figure 26. I<sub>LIMH</sub> vs. T<sub>case</sub>

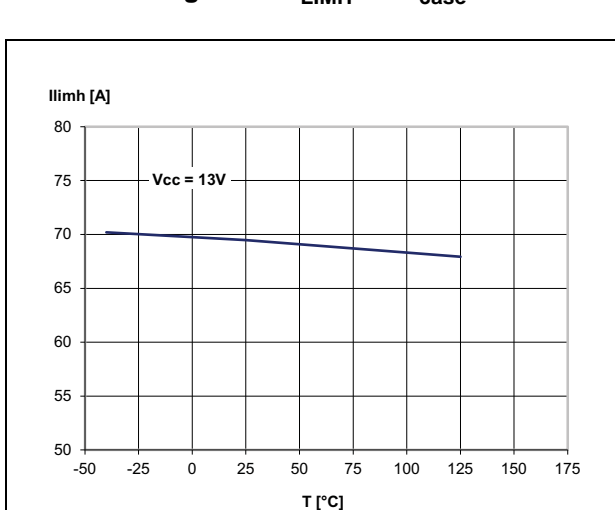


Figure 27. OFF-state open-load voltage detection threshold





Figure 28.  $V_{sense\ clamp}$  vs.  $T_{case}$

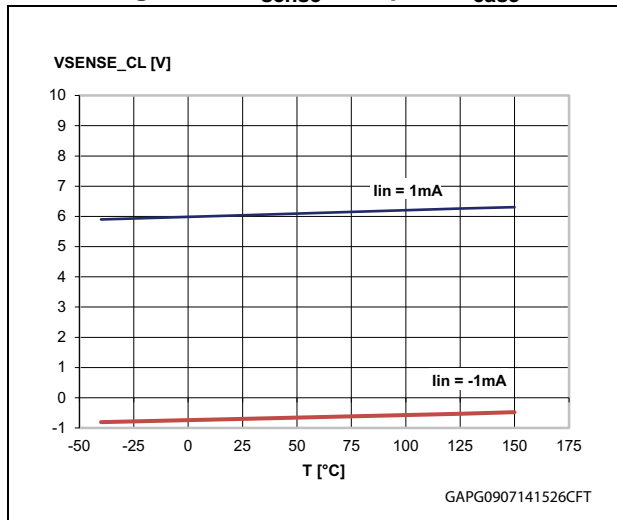
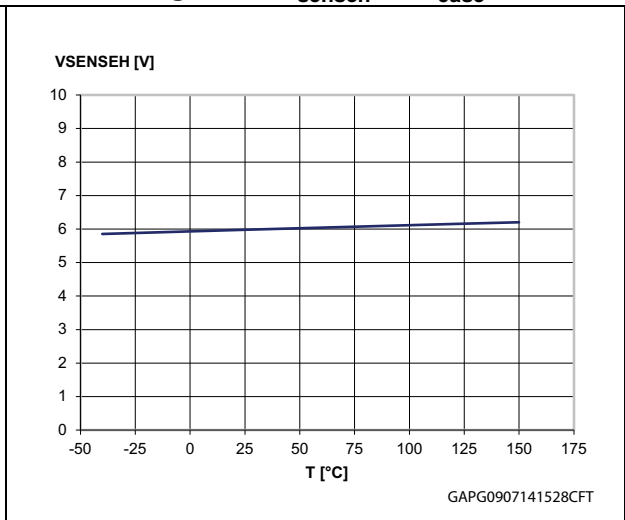


Figure 29.  $V_{senseh}$  vs.  $T_{case}$



## 3 Protections

### 3.1 Power limitation

The basic working principle of this protection consists of an indirect measurement of the junction temperature swing  $\Delta T_j$  through the direct measurement of the spatial temperature gradient on the device surface in order to automatically shut off the output MOSFET as soon as  $\Delta T_j$  exceeds the safety level of  $\Delta T_{j\_SD}$ . According to the voltage level on the FaultRST pin, the output MOSFET switches on and cycles with a thermal hysteresis according to the maximum instantaneous power which can be handled (FaultRST = Low) or remains off (FaultRST = High). The protection prevents fast thermal transient effects and, consequently, reduces thermo-mechanical fatigue.

### 3.2 Thermal shutdown

In case the junction temperature of the device exceeds the maximum allowed threshold (typically 175°C), it automatically switches off and the diagnostic indication is triggered. According to the voltage level on the FaultRST pin, the device switches on again as soon as its junction temperature drops to  $T_R$  (see [Table 8](#), FaultRST = Low) or remains off (FaultRST = High).

### 3.3 Current limitation

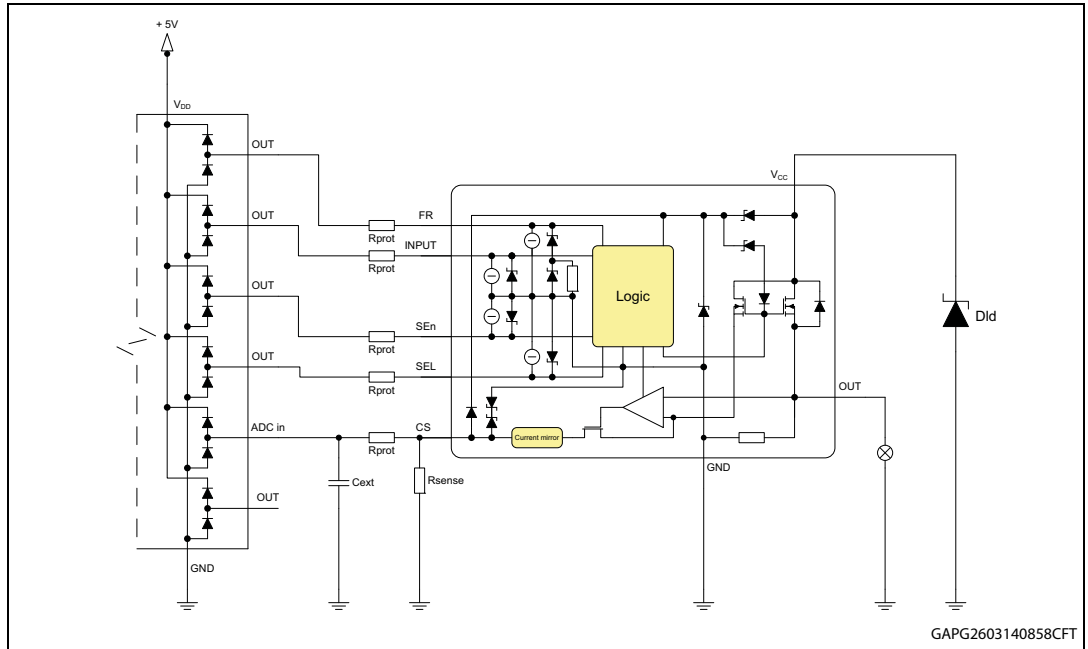
The device is equipped with an output current limiter in order to protect the silicon as well as the other components of the system (e.g. bonding wires, wiring harness, connectors, loads, etc.) from excessive current flow. Consequently, in case of short circuit, overload or during load power-up, the output current is clamped to a safety level,  $I_{LIMH}$ , by operating the output power MOSFET in the active region.

### 3.4 Negative voltage clamp

In case the device drives inductive load, the output voltage reaches negative value during turn off. A negative voltage clamp structure limits the maximum negative voltage to a certain value,  $V_{DEMAG}$  (see [Table 8](#)), allowing the inductor energy to be dissipated without damaging the device.

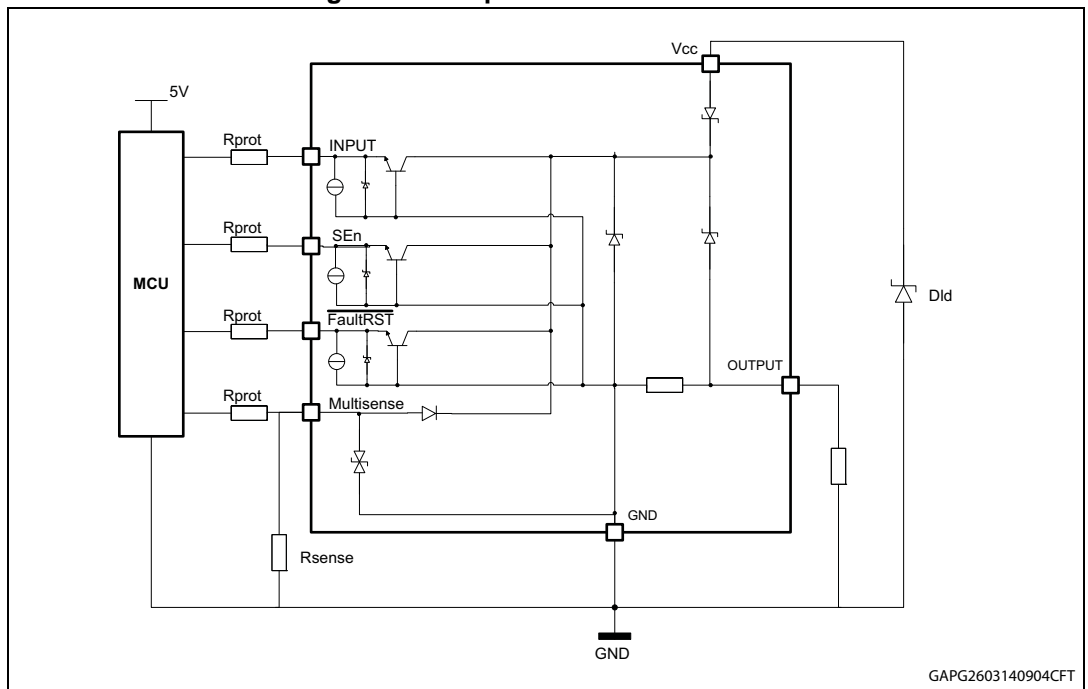
## 4 Application information

Figure 30. Application diagram



### 4.1 GND protection network against reverse battery

Figure 31. Simplified internal structure



The device does not need any external components to protect the internal logic in case of a reverse battery condition. The protection is provided by internal structures.

In addition, due to the fact that the output MOSFET turns on even in reverse battery mode, thus providing the same low ohmic path as in regular operating conditions, no additional power dissipation has to be considered.

## 4.2 Immunity against transient electrical disturbances

The immunity of the device against transient electrical emissions, conducted along the supply lines and injected into the  $V_{CC}$  pin, is tested in accordance with ISO7637-2:2011 (E) and ISO 16750-2:2010.

The related function performance status classification is shown in [Table 12](#).

Test pulses are applied directly to DUT (Device Under Test) both in ON and OFF-state and in accordance to ISO 7637-2:2011(E), chapter 4. The DUT is intended as the present device only, without components and accessed through  $V_{CC}$  and GND terminals.

Status II is defined in ISO 7637-1 Function Performance Status Classification (FPSC) as follows: "The function does not perform as designed during the test but returns automatically to normal operation after the test".

**Table 12. ISO 7637-2 - electrical transient conduction along supply line**

Test Pulse 2011(E)	Test pulse severity level with Status II functional performance status		Minimum number of pulses or test time	Burst cycle / pulse repetition time		Pulse duration and pulse generator internal impedance
	Level	$U_S^{(1)}$		min	max	
1	III	-112V	500 pulses	0,5 s		2ms, 10 $\Omega$
2a	III	+55V	500 pulses	0,2 s	5 s	50 $\mu$ s, 2 $\Omega$
3a	IV	-220V	1h	90 ms	100 ms	0.1 $\mu$ s, 50 $\Omega$
3b	IV	+150V	1h	90 ms	100 ms	0.1 $\mu$ s, 50 $\Omega$
4 <sup>(2)</sup>	IV	-7V	1 pulse			100ms, 0.01 $\Omega$
<b>Load dump according to ISO 16750-2:2010</b>						
Test B <sup>(3)</sup>		40V	5 pulse	1 min		400ms, 2 $\Omega$

1.  $U_S$  is the peak amplitude as defined for each test pulse in ISO 7637-2:2011(E), chapter 5.6.

2. Test pulse from ISO 7637-2:2004(E).

3. With 40 V external suppressor referred to ground ( $-40^\circ\text{C} < T_j < 150^\circ\text{C}$ ).

## 4.3 MCU I/Os protection

If a ground protection network is used and negative transients are present on the  $V_{CC}$  line, the control pins will be pulled negative. ST suggests to insert a resistor ( $R_{prot}$ ) in line both to prevent the microcontroller I/O pins to latch-up and to protect the HSD inputs.

The value of these resistors is a compromise between the leakage current of microcontroller and the current required by the HSD I/Os (Input levels compatibility) with the latch-up limit of microcontroller I/Os.

**Equation 1**

$$V_{CCpeak}/I_{latchup} \leq R_{prot} \leq (V_{OH\mu C} - V_{IH} - V_{GND}) / I_{IHmax}$$

Calculation example:

For  $V_{CCpeak} = -150\text{ V}$ ;  $I_{latchup} \geq 20\text{ mA}$ ;  $V_{OH\mu C} \geq 4.5\text{ V}$

$$7.5\text{ k}\Omega \leq R_{prot} \leq 140\text{ k}\Omega.$$

Recommended values:  $R_{prot} = 15\text{ k}\Omega$

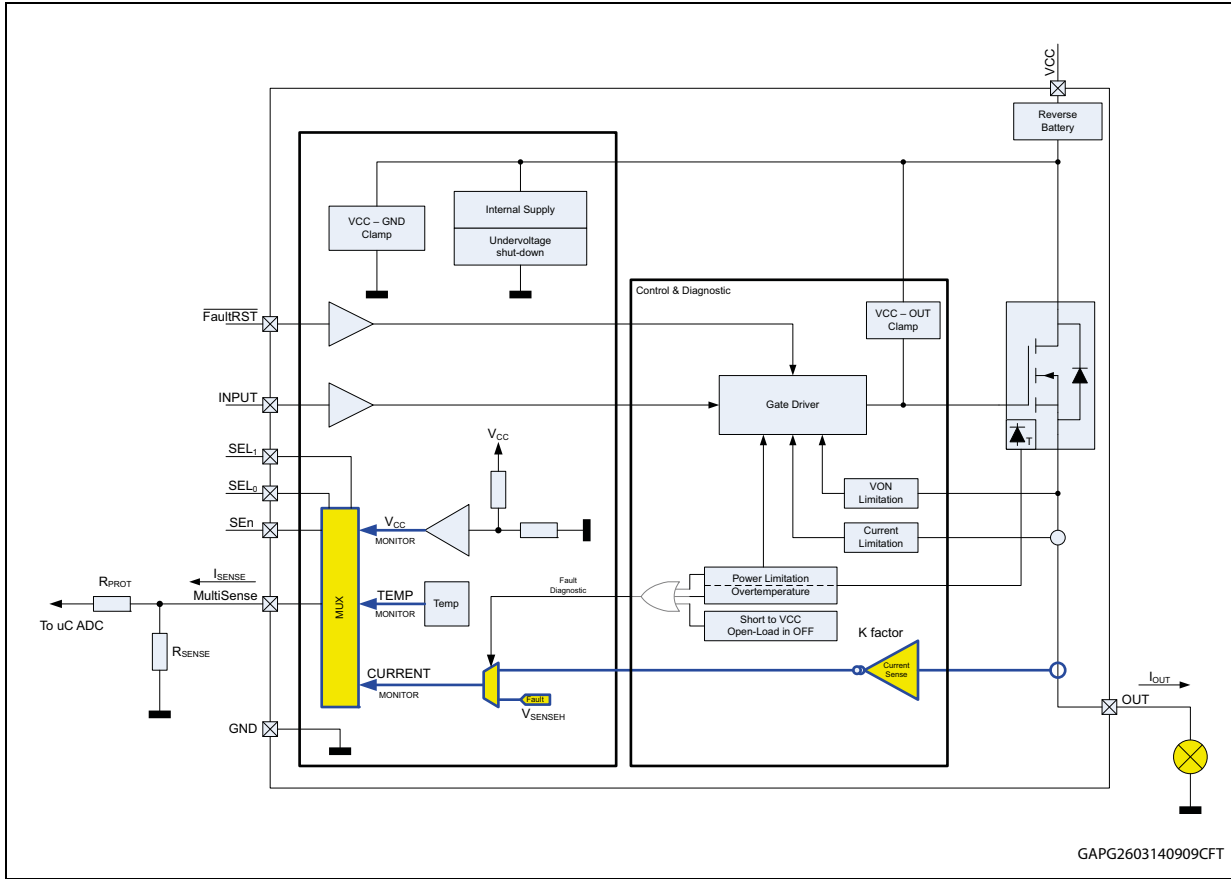
## 4.4 MultiSense - analog current sense

Diagnostic information on device and load status are provided by an analog output pin (MultiSense) delivering the following signals:

- Current monitor: current mirror of channel output current
- $V_{CC}$  monitor: voltage proportional to  $V_{CC}$
- $T_{CASE}$ : voltage proportional to chip temperature

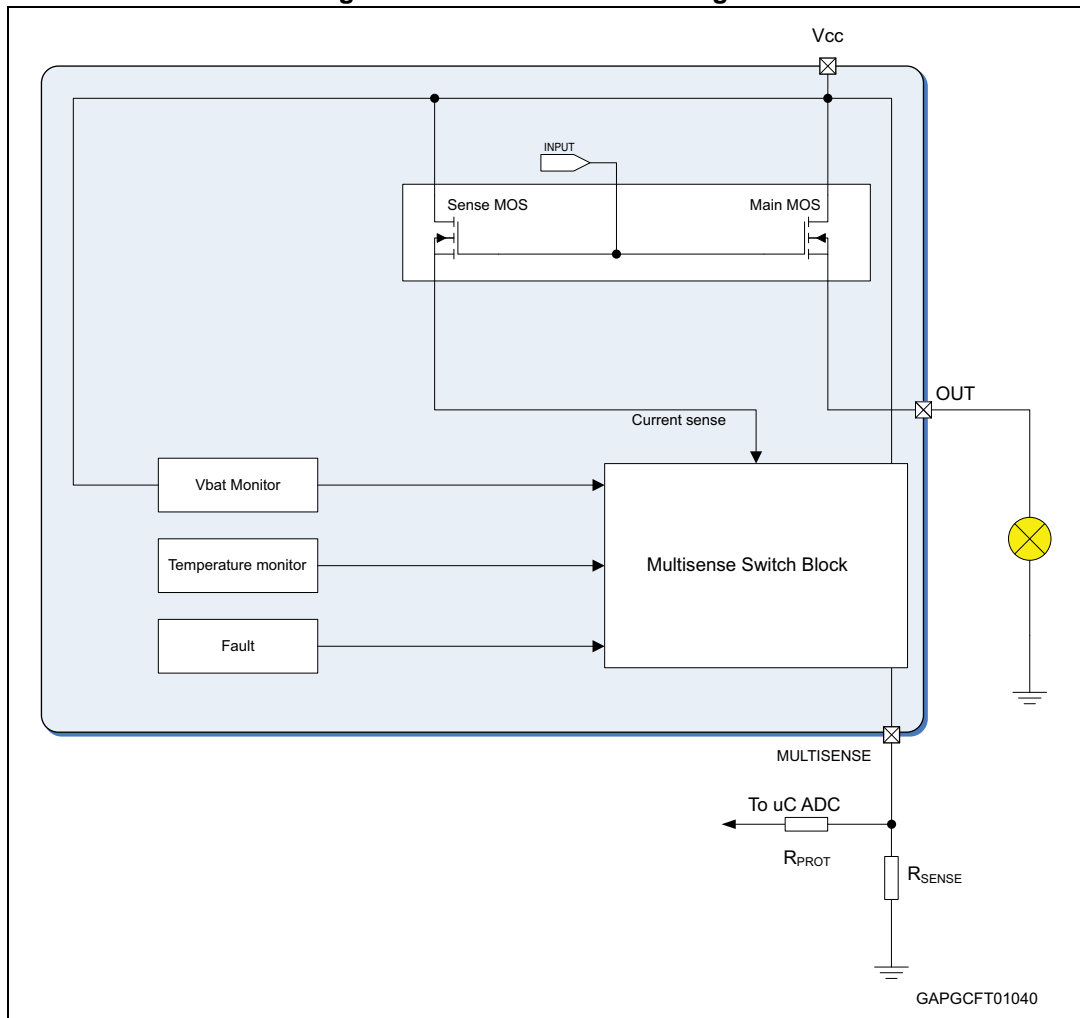
Those signals are routed through an analog multiplexer which is configured and controlled by means of SELx and SEN pins, according to the address map in [Table 11](#).

Figure 32. MultiSense and diagnostic – block diagram



#### 4.4.1 Principle of MultiSense signal generation

Figure 33. MultiSense block diagram



##### Current monitor

When current mode is selected in the MultiSense, this output is capable to provide:

- **Current mirror proportional to the load current in normal operation**, delivering current proportional to the load according to known ratio named **K**
- **Diagnostics flag in fault conditions** delivering fixed voltage  $V_{SENSEH}$

The current delivered by the current sense circuit,  $I_{SENSE}$ , can be easily converted to a voltage  $V_{SENSE}$  by using an external sense resistor,  $R_{SENSE}$ , allowing continuous load monitoring and abnormal condition detection.

##### Normal operation (channel ON, no fault, SEn active)

While device is operating in normal conditions (no fault intervention),  $V_{SENSE}$  calculation can be done using simple equations

Current provided by MultiSense output:  $I_{SENSE} = I_{OUT}/K$

Voltage on  $R_{SENSE}$ :  $V_{SENSE} = R_{SENSE} \cdot I_{SENSE} = R_{SENSE} \cdot I_{OUT}/K$

Where :

- $V_{SENSE}$  is voltage measurable on  $R_{SENSE}$  resistor
- $I_{SENSE}$  is current provided from MultiSense pin in current output mode
- $I_{OUT}$  is current flowing through output
- K factor represents the ratio between PowerMOS cells and SenseMOS cells; its spread includes geometric factor spread, current sense amplifier offset and process parameters spread of overall circuitry specifying ratio between  $I_{OUT}$  and  $I_{SENSE}$ .

**Failure flag indication**

In case of power limitation/overtemperature, the fault is indicated by the MultiSense pin which is switched to a “current limited” voltage source,  $V_{SENSEH}$  (see [Table 9](#)).

In any case, the current sourced by the MultiSense in this condition is limited to  $I_{SENSEH}$  (see [Table 9](#)).

**Figure 34. Analogue HSD – open-load detection in off-state**

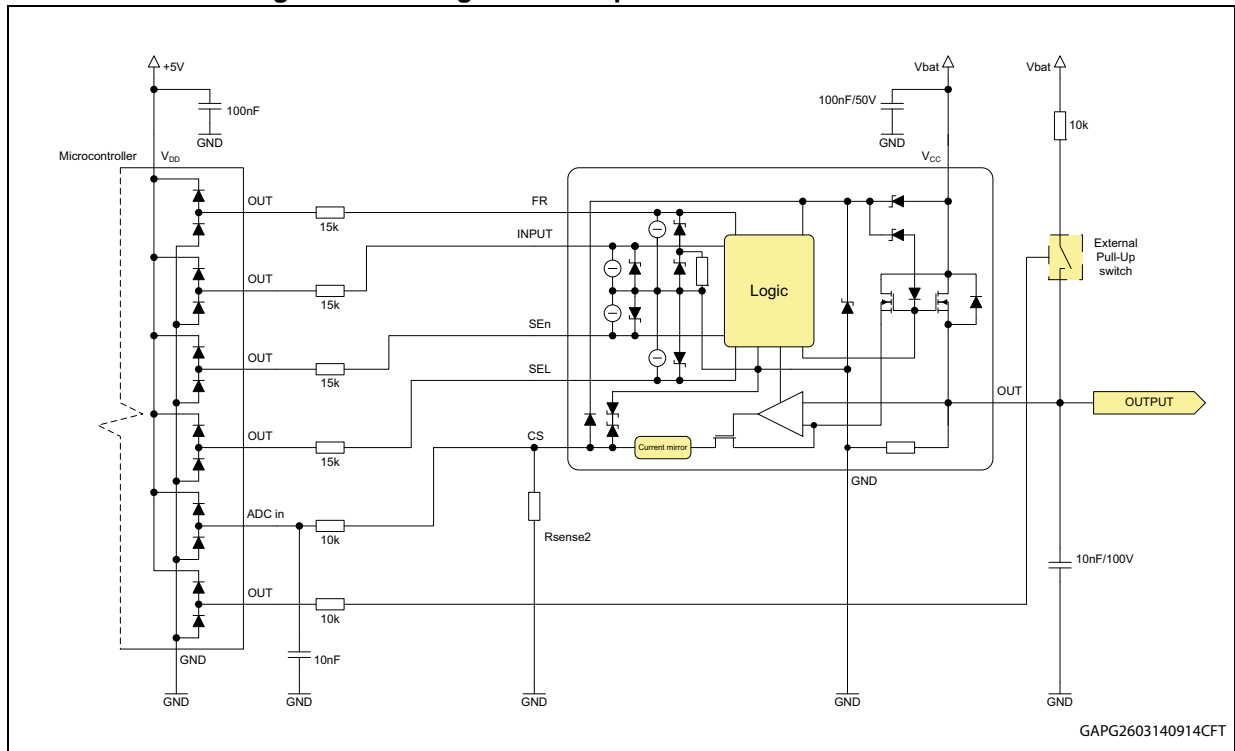




Figure 35. Open-load / short to V<sub>CC</sub> condition

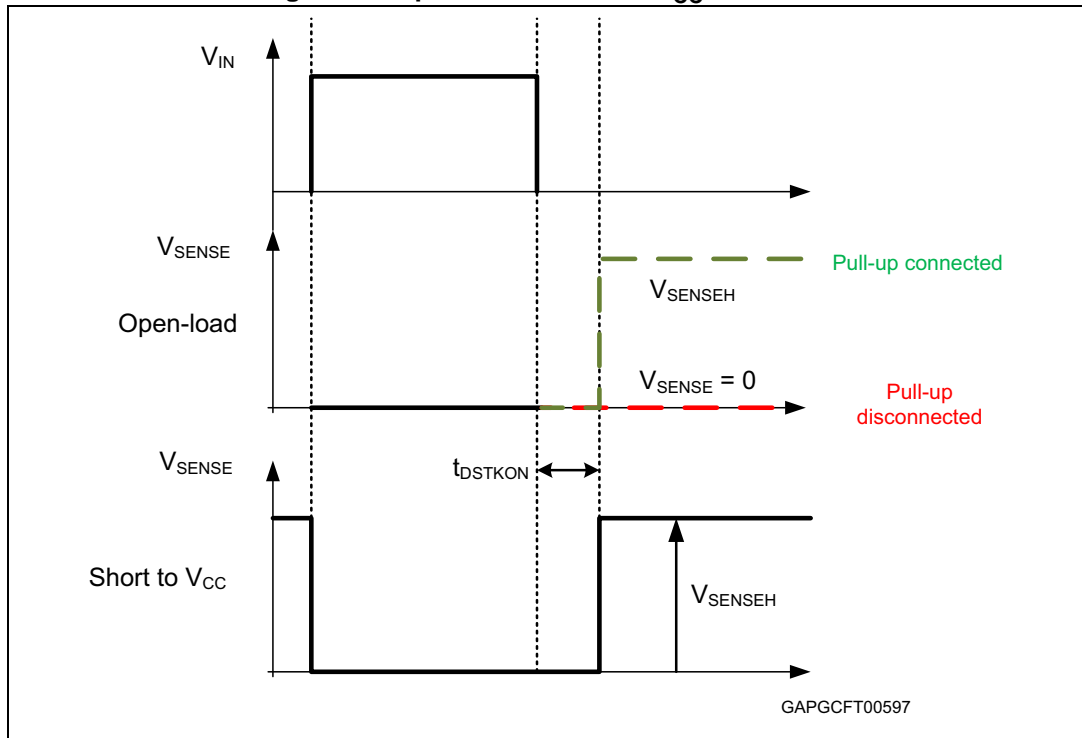


Table 13. MultiSense pin levels in off-state

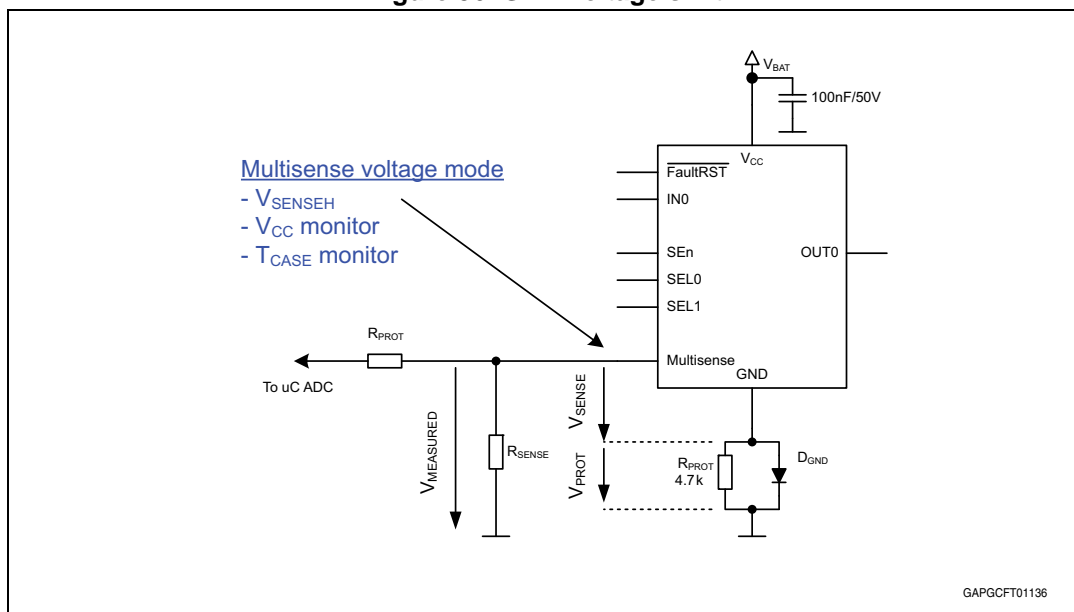
Condition	Output	MultiSense	SEn
Open-load	$V_{OUT} > V_{OL}$	Hi-Z	L
		$V_{SENSEH}$	H
Open-load	$V_{OUT} < V_{OL}$	Hi-Z	L
		0	H
Short to V <sub>CC</sub>	$V_{OUT} > V_{OL}$	Hi-Z	L
		$V_{SENSEH}$	H
Nominal	$V_{OUT} < V_{OL}$	Hi-Z	L
		0	H

#### 4.4.2 T<sub>CASE</sub> and V<sub>CC</sub> monitor

In this case, MultiSense output operates in voltage mode and output level is referred to device GND. Care must be taken in case a GND network protection is used, because of a voltage shift is generated between device GND and the microcontroller input GND reference.

Figure 36 shows link between V<sub>MEASURED</sub> and real V<sub>SENSE</sub> signal.

Figure 36. GND voltage shift



**V<sub>CC</sub> monitor**

Battery monitoring channel provides  $V_{SENSE} = V_{CC} / 4$ .

**Case temperature monitor**

Case temperature monitor is capable to provide information about the actual device temperature. Since a diode is used for temperature sensing, the following equation describes the link between temperature and output  $V_{SENSE}$  level:

$$V_{SENSE\_TC}(T) = V_{SENSE\_TC}(T_0) + dV_{SENSE\_TC} / dT * (T - T_0)$$

where  $dV_{SENSE\_TC} / dT \sim$  typically  $-5.5 \text{ mV/K}$  (for temperature range  $(-40 \text{ }^\circ\text{C}$  to  $150 \text{ }^\circ\text{C})$ ).

**4.4.3 Short to V<sub>CC</sub> and OFF-state open-load detection**

**Short to V<sub>CC</sub>**

A short circuit between  $V_{CC}$  and output is indicated by the relevant current sense pin set to  $V_{SENSEH}$  during the device off-state. Small or no current is delivered by the current sense during the on-state depending on the nature of the short circuit.

**OFF-state open-load with external circuitry**

Detection of an open-load in off mode requires an external pull-up resistor  $R_{PU}$  connecting the output to a positive supply voltage  $V_{PU}$ .

It is preferable  $V_{PU}$  to be switched off during the module standby mode in order to avoid the overall standby current consumption to increase in normal conditions, i.e. when load is connected.

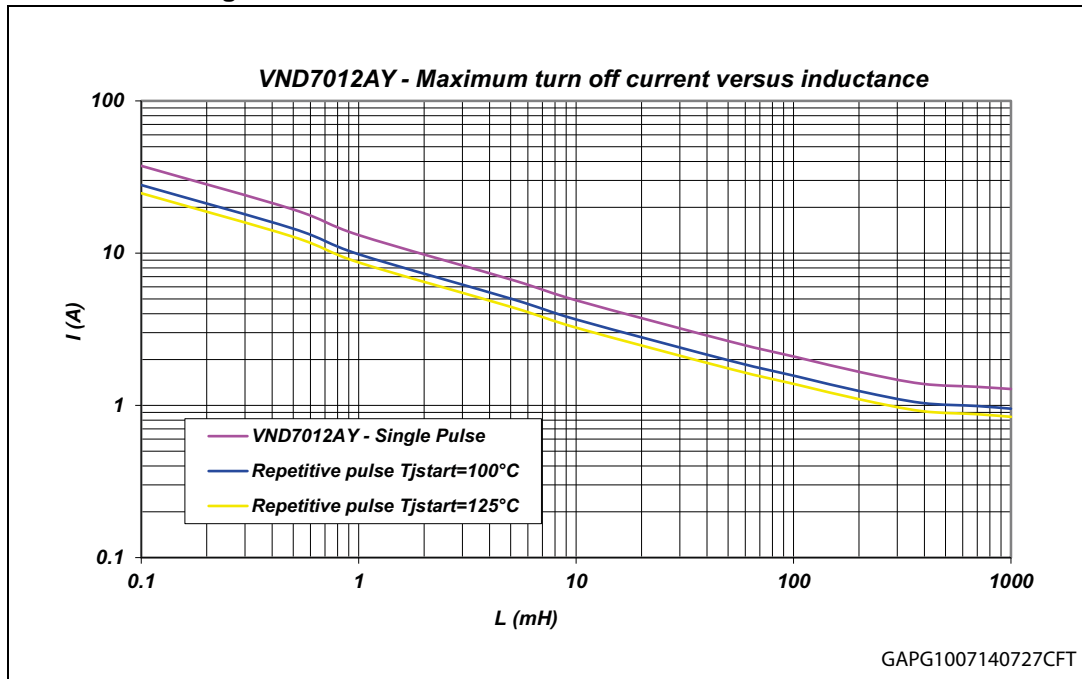
$R_{PU}$  must be selected in order to ensure  $V_{OUT} > V_{OLmax}$  in accordance with the following equation:

**Equation 2**

$$R_{PU} < \frac{V_{PU} - 4}{I_{L(off2)min @ 4V}}$$

**4.5 Maximum demagnetization energy ( $V_{CC} = 16 V$ )**

**Figure 37. Maximum turn off current versus inductance**



- Values are generated with  $R_L = 0 \Omega$ .  
In case of repetitive pulses,  $T_{jstart}$  (at the beginning of each demagnetization) of every pulse must not exceed the temperature specified above for curves A and B.

## 5 Package and PCB thermal data

### 5.1 PowerSSO-36 thermal data

Figure 38. PowerSSO-36 PCB board

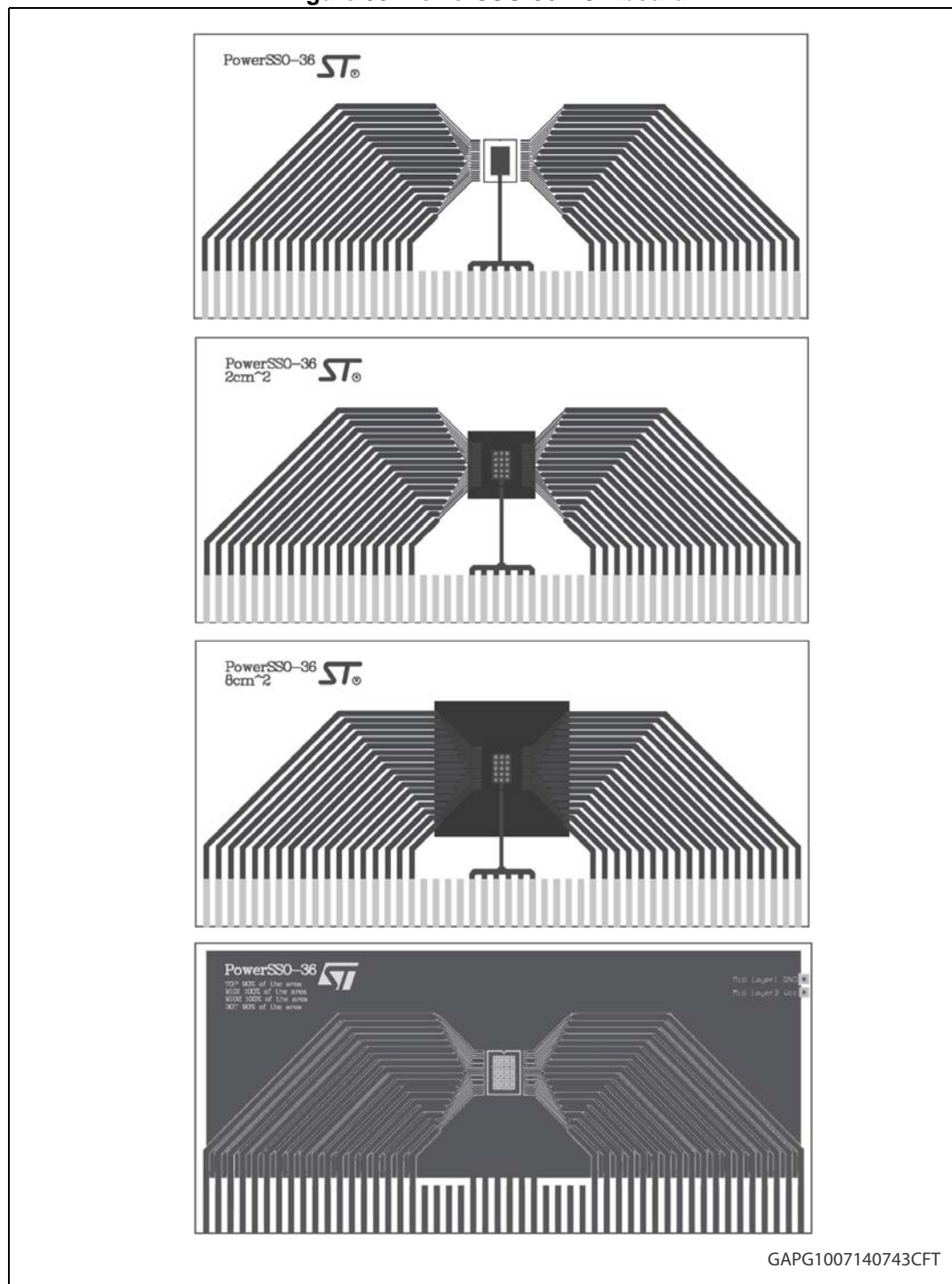


Table 14. PCB properties

Dimension	Value
Board finish thickness	1.6 mm +/- 10%
Board dimension	129 mm x 86 mm
Board material	FR4
Cu thickness (outer layers)	0.070 mm
Cu thickness (inner layers)	0.035 mm
Thermal via separation	1.2 mm
Thermal via diameter	0.3 mm +/- 0.08 mm
Cu thickness on vias	0.025 mm
Footprint dimension	4.1 mm x 6.5 mm

Figure 39.  $R_{thj-amb}$  vs PCB copper area in open box free air condition (one channel on)

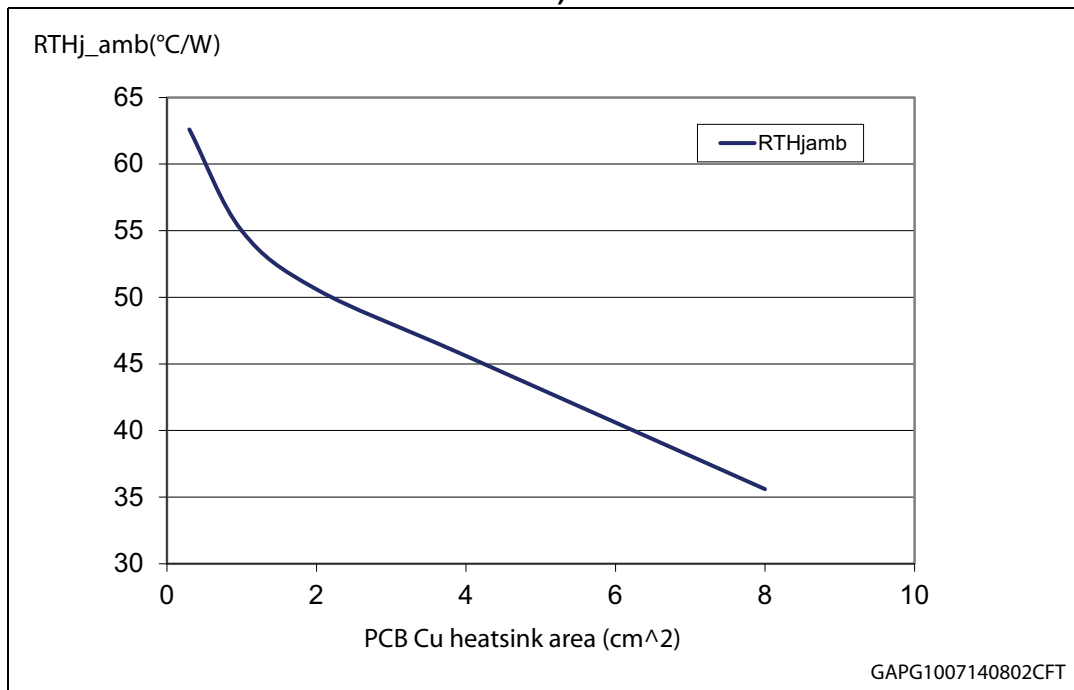
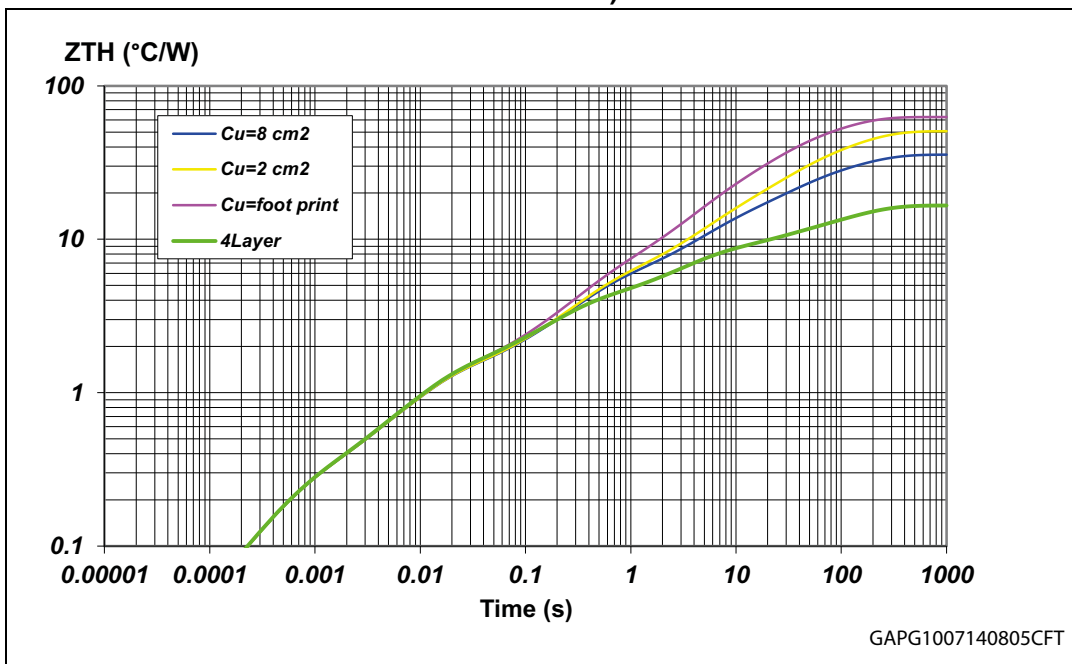


Figure 40. PowerSSO-16 thermal impedance junction ambient single pulse (one channel on)

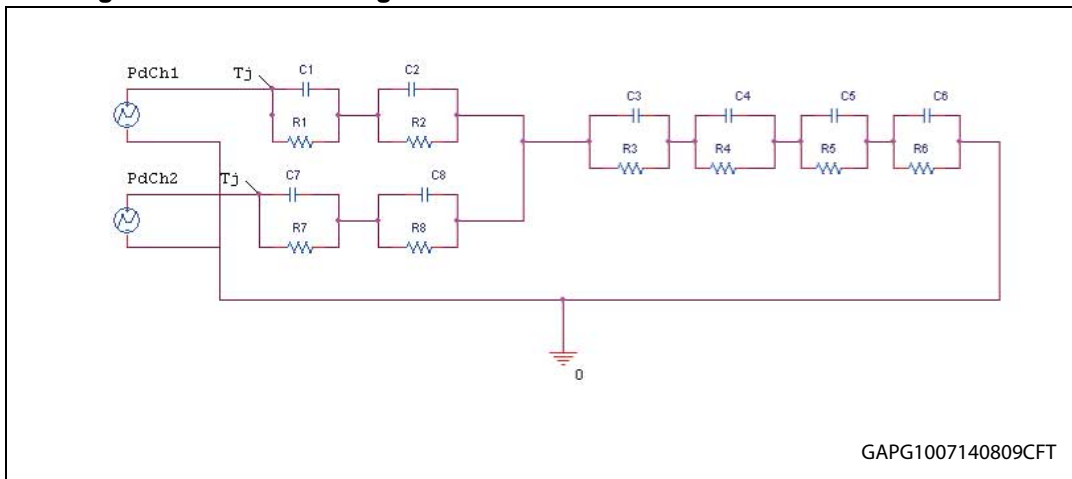


Equation 3: pulse calculation formula

$$Z_{TH\delta} = R_{TH} \cdot \delta + Z_{THtp}(1 - \delta)$$

where  $\delta = t_p/T$

Figure 41. Thermal fitting model of a double-channel HSD in PowerSSO-16



1. The fitting model is a simplified thermal tool and is valid for transient evolutions where the embedded protections (power limitation or thermal cycling during thermal shutdown) are not triggered.

Table 15. Thermal parameters

Area/island (cm <sup>2</sup> )	Footprint	2	8	4L
R1 = R7 (°C/W)	0.2			
R2 = R8 (°C/W)	1			
R3 (°C/W)	3.4	3.4	3.4	2.4
R4 (°C/W)	8	6	6	4
R5 (°C/W)	20	14	10	2
R6 (°C/W)	30	26	15	7
C1 = C7 (W.s/°C)	0.0025			
C2 = C8 (W.s/°C)	0.01			
C3 (W.s/°C)	0.1	0.1	0.1	0.8
C4 (W.s/°C)	0.5	0.8	0.8	0.8
C5 (W.s/°C)	1	2	3	10
C6 (W.s/°C)	3	5	9	18

## 6 Package information

### 6.1 ECOPACK®

In order to meet environmental requirements, ST offers these devices in different grades of ECOPACK® packages, depending on their level of environmental compliance. ECOPACK® specifications, grade definitions and product status are available at [www.st.com](http://www.st.com).

ECOPACK® is an ST trademark.

### 6.2 PowerSSO-36 mechanical data

Figure 42. PowerSSO-36 package dimensions

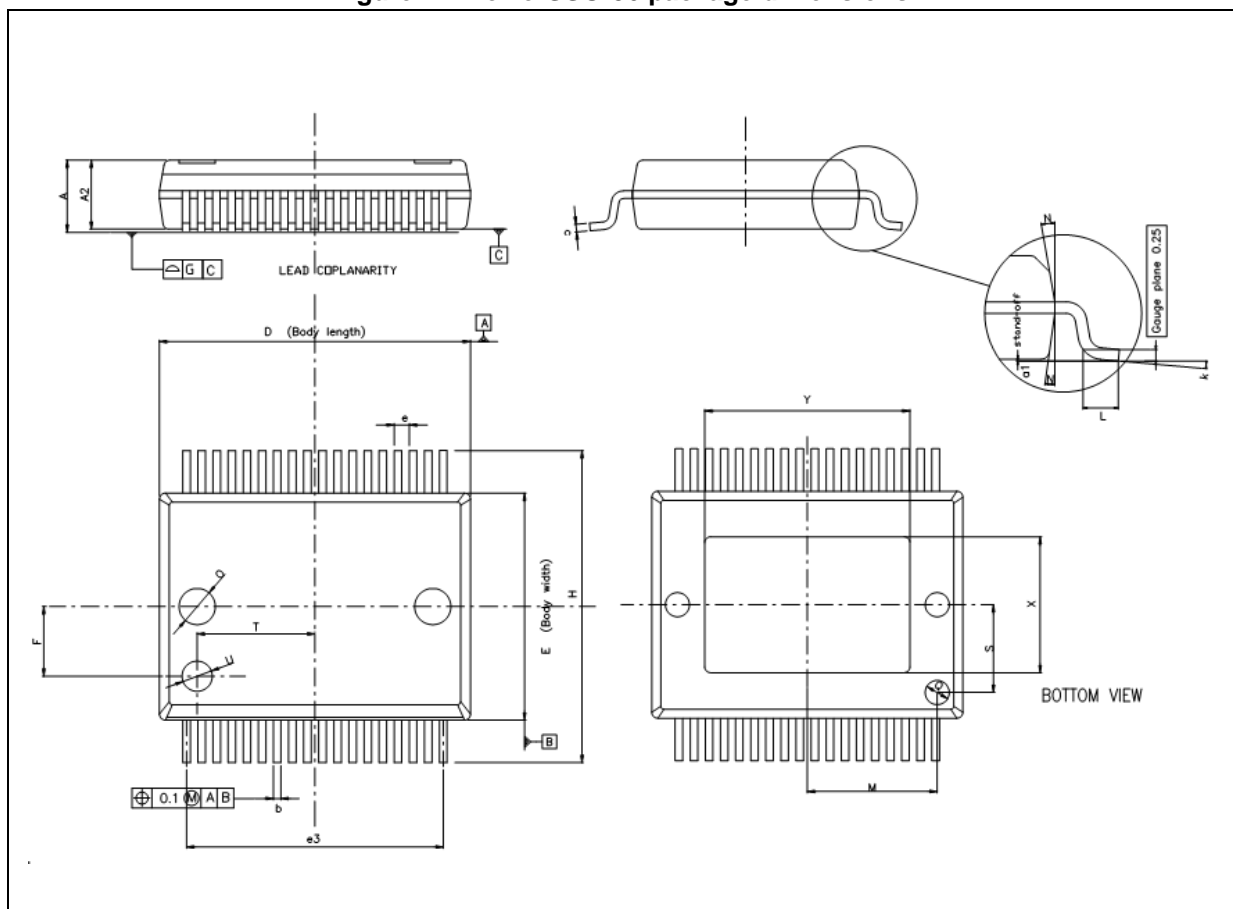




Table 16. PowerSSO-36 mechanical data

Symbol	millimeters		
	Min	Typ	Max
A	2.15	-	2.45
A2	2.15	-	2.35
a1	0	-	0.1
b	0.18	-	0.36
c	0.23	-	0.32
D	10.10	-	10.50
E	7.4	-	7.6
e	-	0.5	-
e3	-	8.5	-
F	-	2.3	-
G	-	-	0.1
H	10.1	-	10.5
h	-	-	0.4
k	0°	-	8°
L	0.55	-	0.85
M	-	4.3	-
N	-	-	10°
O	-	1.2	-
Q	-	0.8	-
S	-	2.9	-
T	-	3.65	-
U	-	1.0	-
X <sup>(1)</sup>	4.3	-	5.2
Y <sup>(1)</sup>	6.9	-	7.5

1. Corresponding to internal variation C.

### 6.3 Packing information

Figure 43. PowerSSO-36 tube shipment (no suffix)

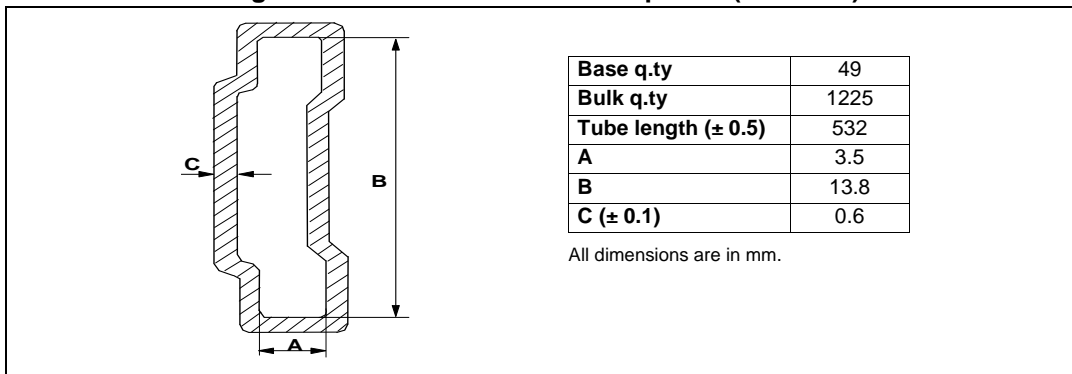
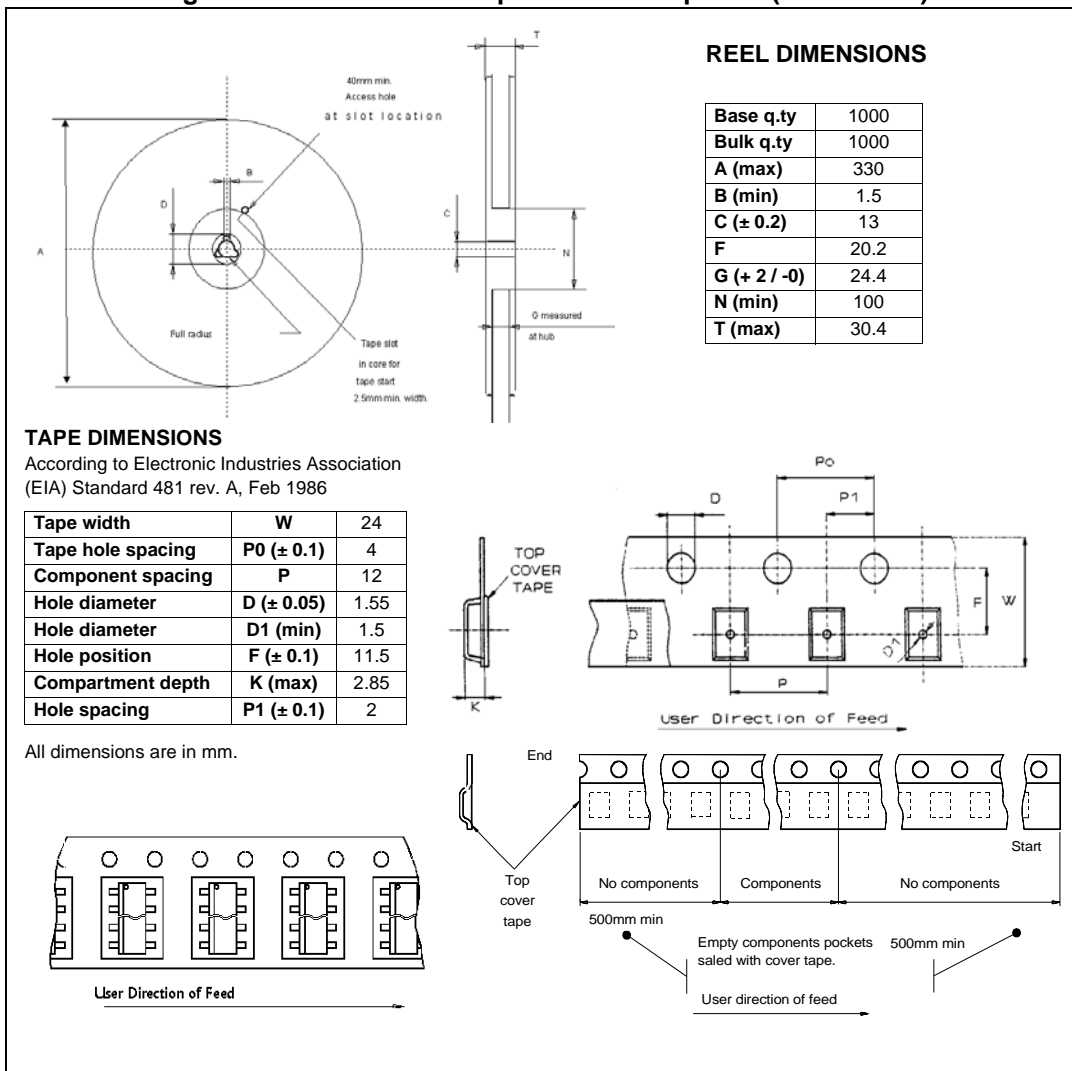


Figure 44. PowerSSO-36 tape and reel shipment (suffix "TR")



## 7 Order codes

**Table 17. Device summary**

Package	Order codes	
	Tube	Tape and reel
PowerSSO-36	VND7012AY-E	VND7012AYTR-E

## 8 Revision history

**Table 18. Document revision history**

Date	Revision	Changes
05-Mar-2012	1	Initial release.
18-Feb-2013	2	<p><i>Table 1: Pin functions:</i></p> <ul style="list-style-type: none"> <li>– GND: updated functions definitions</li> </ul> <p>Updated <i>Figure 2: Configuration diagram (top view)</i></p>
25-Mar-2013	3	<p>Updated <i>Features</i> list</p> <p><i>Table 3: Absolute maximum ratings:</i></p> <ul style="list-style-type: none"> <li>– <math>I_{OUT}</math>, <math>V_{ESD}</math>: updated value</li> <li>– <math>I_{SENSE}</math>, <math>E_{MAX}</math>: updated parameter and value</li> </ul> <p>Updated <i>Table 4: Thermal data</i></p> <p><i>Table 5: Power section:</i></p> <ul style="list-style-type: none"> <li>– <math>V_{clamp}</math>: added test conditions and value</li> <li>– <math>I_{STBY}</math>, <math>t_{D\_STBY}</math>, <math>I_{L(off)}</math>: updated test conditions</li> <li>– <math>I_{GND(ON)}</math>: updated test conditions and value</li> <li>– <math>V_F</math>: added row</li> </ul> <p>Updated <i>Table 6: Switching (<math>V_{CC} = 13\text{ V}</math>; <math>-40\text{ }^\circ\text{C} &lt; T_j &lt; 150\text{ }^\circ\text{C}</math>, unless otherwise specified)</i></p> <p><i>Table 8: Protections (<math>7\text{ V} &lt; V_{CC} &lt; 18\text{ V}</math>; <math>-40\text{ }^\circ\text{C} &lt; T_j &lt; 150\text{ }^\circ\text{C}</math>):</i></p> <ul style="list-style-type: none"> <li>– <math>I_{LIMH}</math>: added note</li> <li>– <math>T_R</math>, <math>T_{HYST}</math>: added note and updated value</li> <li>– <math>\Delta T_{J\_SD}</math>: updated test conditions</li> <li>– <math>t_{LATCH\_RST}</math>: added note and updated test conditions</li> </ul> <p><i>Table 9: MultiSense (<math>7\text{ V} &lt; V_{CC} &lt; 18\text{ V}</math>; <math>-40\text{ }^\circ\text{C} &lt; T_j &lt; 150\text{ }^\circ\text{C}</math>):</i></p> <ul style="list-style-type: none"> <li>– <math>V_{SENSE\_CL}</math>, <math>t_{DSENSE1H}</math>, <math>t_{DSENSE1L}</math>, <math>t_{DSENSE2H}</math>, <math>\Delta t_{DSENSE2L}</math>, <math>t_{DSENSE2L}</math>, <math>t_{D\_CS to TC}</math>, <math>t_{D\_TC to CS}</math>, <math>t_{D\_CS to VCC}</math>, <math>t_{D\_VCC to CS}</math>, <math>t_{D\_CS to VSENSEH}</math>: updated test conditions</li> <li>– <math>K_{OL}</math>, <math>dK_{cal}/K_{cal}</math>, <math>K_{LED}</math>, <math>I_{OUT\_SAT}</math>: added rows</li> <li>– <math>K_0</math>, <math>dK_0/K_0</math>, <math>K_1</math>, <math>dK_1/K_1</math>, <math>K_2</math>, <math>dK_2/K_2</math>, <math>K_3</math>, <math>dK_3/K_3</math>, <math>t_{D\_OL\_V}</math>, <math>V_{SENSEH}</math>, <math>I_{SENSEH}</math>: updated values</li> <li>– <math>I_{SENSE0}</math>: added test conditions and values</li> <li>– <math>V_{SENSE\_SAT}</math>, <math>I_{SENSE\_SAT}</math>, <math>I_{L(off2)}</math>, <math>V_{SENSE\_TC}</math>, <math>V_{SENSE\_CC}</math>: updated test conditions and values</li> </ul> <p>Removed <i>Figure: Switching times</i> and <i>Figure: Pulse skew</i></p> <p>Added <i>Figure 6: Switching times and Pulse skew</i> and <i>Figure 9: <math>T_{DSKON}</math></i></p> <p><i>Table 10: Truth table:</i></p> <ul style="list-style-type: none"> <li>– Updated overload condition</li> </ul> <p><i>Table 11: MultiSense multiplexer addressing:</i></p> <ul style="list-style-type: none"> <li>– Added note and updated negative output</li> </ul>
18-Sep-2013	4	Updated disclaimer.

Table 18. Document revision history

Date	Revision	Changes
16-Jan-2014	5	<p><i>Table 5: Power section:</i></p> <ul style="list-style-type: none"> <li>– <math>V_F</math>: updated test conditions</li> </ul> <p>Updated <i>Table 6: Switching</i> (<math>V_{CC} = 13\text{ V}</math>; <math>-40\text{ }^\circ\text{C} &lt; T_j &lt; 150\text{ }^\circ\text{C}</math>, unless otherwise specified)</p> <p><i>Table 9: MultiSense</i> (<math>7\text{ V} &lt; V_{CC} &lt; 18\text{ V}</math>; <math>-40\text{ }^\circ\text{C} &lt; T_j &lt; 150\text{ }^\circ\text{C}</math>):</p> <ul style="list-style-type: none"> <li>– <math>K_{OL}</math>, <math>dK_{cal}/K_{cal}</math>, <math>K_{LED}</math>, <math>K_0</math>, <math>K_1</math>, <math>K_2</math>, <math>K_3</math>, <math>I_{OUT\_SAT}</math>: updated values</li> </ul>
14-Jul-2014	6	<p><i>Table 3: Absolute maximum ratings:</i></p> <ul style="list-style-type: none"> <li>– <math>E_{MAX}</math>: updated value</li> </ul> <p>Updated <i>Table 4: Thermal data</i> and <i>Table 6: Switching</i> (<math>V_{CC} = 13\text{ V}</math>; <math>-40\text{ }^\circ\text{C} &lt; T_j &lt; 150\text{ }^\circ\text{C}</math>, unless otherwise specified)</p> <p><i>Table 9: MultiSense</i> (<math>7\text{ V} &lt; V_{CC} &lt; 18\text{ V}</math>; <math>-40\text{ }^\circ\text{C} &lt; T_j &lt; 150\text{ }^\circ\text{C}</math>):</p> <ul style="list-style-type: none"> <li>– <math>K_{OL}</math>, <math>K_{LED}</math>, <math>K_1</math>, <math>K_2</math>, <math>K_3</math>: updated values</li> </ul> <p>Added <i>Figure 4: <math>I_{OUT}/I_{SENSE}</math> vs. <math>I_{OUT}</math></i> and <i>Figure 5: Current sense precision vs. <math>I_{OUT}</math></i></p> <p>Removed <i>Table: Electrical transient requirements (part 1)</i>, <i>Table: Electrical transient requirements (part 2)</i>, and <i>Table: Electrical transient requirements (part 3)</i> and <i>Section: Waveforms</i></p> <p>Added <i>Chapter 3: Protections</i>, <i>Chapter 4: Application information</i> and <i>Chapter 5: Package and PCB thermal data</i></p>

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